

MILITARY SPECIFICATION

MICROCIRCUITS, DIGITAL, HIGH SPEED, CMOS,
BUS TRANSCEIVERS WITH THREE-STATE OUTPUTS,
MONOLITHIC SILICON

This specification is approved for use by all Departments and Agencies of the Department of Defense.

1. SCOPE

1.1 Scope. This specification covers the detail requirements for monolithic silicon, high speed, CMOS, logic microcircuits. Two product assurance classes and a choice of case outlines and lead finishes are provided and are reflected in the complete part number.

1.2 Part number. The part number shall be in accordance with MIL-M-38510, and as specified herein.

1.2.1 Device type. The device types shall be as follows:

<u>Device type</u>	<u>Circuit</u>
01	Quadruple inverting bus transceivers with three-state outputs
02	Quadruple non-inverting bus transceivers with three-state outputs
03	Octal non-inverting bus transceivers with three-state outputs
04, 05	To be included later
06	Octal inverting bus transceivers with three-state outputs
07	Octal non-inverting or inverting bus transceivers with three-state outputs
08	Octal non-inverting bus transceivers with three-state outputs
09	Octal inverting bus transceivers with three-state outputs
53	Octal non-inverting bus transceivers with three-state outputs and TTL-input voltage compatibility

1.2.2 Device class. The device class shall be the product assurance level as defined in MIL-M-38510.

1.2.3 Case outlines. The case outlines shall be designated as follows:

<u>Outline letter</u>	<u>Case outline (see MIL-M-38510, appendix C)</u>
C	D-1 (14-lead, 1/4" x 3/4"), dual-in-line package
L	D-9 (24-lead, 1/4" x 1 1/4"), dual-in-line package
R	D-8 (20-lead, 1/4" x 1 1/16"), dual-in-line package
2	C-2 (20-terminal, .350" x .350") square chip carrier package
3	C-4 (28-terminal, .450" x .450"), square chip carrier package

Beneficial comments (recommendations, additions, deletions) and any pertinent data which may be of use in improving this document should be addressed to: Rome Air Development Center (RBE-2), Griffiss AFB, NY 13441, by using the self-addressed Standardization Document Improvement Proposal (DD Form 1426) appearing at the end of this document or by letter.

1.3 Absolute maximum ratings.

Supply voltage (V_{CC})	- - - - -	-0.5 V dc to +7.0 V dc
DC input voltage (V_{IN})	- - - - -	-0.5 V dc to V_{CC} +0.5 V dc
DC output voltage (V_{OUT})	- - - - -	-0.5 V dc to V_{CC} +0.5 V dc
Clamp diode current (I_{IK}, I_{QK})	- - - - -	±20 mA
DC output current per pin (I_{OUT})	- - - - -	±35 mA
DC V_{CC} or GND current per pin (I_{OC})	- - - - -	±70 mA
Storage temperature range (T_{STG})	- - - - -	-65°C to +150°C
Maximum power dissipation (P_D)	- - - - -	300 mW
Lead temperature (soldering, 10 seconds)	- - - - -	+300°C
Thermal resistance, junction-to-case (θ_{JC}):		
Cases C, L, and R	- - - - -	(See MIL-M-38510, appendix C) 60°C/W
Case 2	- - - - -	TBD
Case 3	- - - - -	+175°C
Junction temperature (T_J)	- - - - -	

1.4 Recommended operating conditions.Device types 01, 02, 03, 06, 07, 08, 09:

Input low (V_{IL}) maximum voltage	- - - - -	0.3 V at $V_{CC} = 2$ V 0.9 V at $V_{CC} = 4.5$ V 1.2 V at $V_{CC} = 6$ V
Input high (V_{IH}) minimum voltage	- - - - -	1.5 V at $V_{CC} = 3$ V 3.15 V at $V_{CC} = 4.5$ V 4.2 V at $V_{CC} = 6$ V
Operating ambient temperature range T_A	- - - - -	-55°C to +125°C
Width of clock pulse (t_{CLK}):		
Device types 08 and 09	- - - - -	27 ns minimum
Setup time before clock (t_{setup}):		
Device types 08 and 09	- - - - -	30 ns minimum
Hold time (t_{hold}):		
Device types 08 and 09	- - - - -	8 ns minimum
Supply voltage (V_{CC})	- - - - -	2 V dc to 6 V dc
Output voltage	- - - - -	0 V dc to V_{CC}

Input rise and fall times (t_r, t_f) maximum:

$V_{CC} = 2$ V	1000 ns
$V_{CC} = 4.5$ V	500 ns
$V_{CC} = 6$ V	400 ns

Device type 53:

Input low (V_{IL}) maximum voltage	- - - - -	0.8 V at $V_{CC} = 4.5$ V - 5.5 V
Input high (V_{IH}) minimum voltage	- - - - -	2.0 V at $V_{CC} = 4.5$ V - 5.5 V
Supply voltage (V_{CC})	- - - - -	4.5 V dc to 5.5 V dc
Output voltage	- - - - -	0 V dc to V_{CC}
Operating ambient temperature T_A	- - - - -	-55°C to +125°C

Input rise and fall times (t_r, t_f):

$V_{CC} = 4.5$ V	500 ns maximum
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2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this specification to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this specification and the references cited herein (except for associated detail specifications, specification sheets or MS standards), the text of this specification shall take precedence. Nothing in this specification, however, shall supersede applicable laws and regulations unless a specific exemption has been obtained.

3. REQUIREMENTS

3.1 Detail specification. The individual item requirements shall be in accordance with MIL-M-38510, and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Logic diagrams and terminal connections. The logic diagrams and terminal connections shall be as specified on figure 1.

3.2.2 Truth tables and logic equations. The truth tables shall be as specified on figure 2.

3.2.3 Schematic circuits. The schematic circuits shall be submitted to the preparing activity prior to inclusion of a manufacturer's device in this specification and shall be submitted to the qualifying activity as a prerequisite for qualification. All qualified manufacturers' schematics shall be maintained and available upon request.

3.3 Lead material and finish. The lead material and finish shall be in accordance with MIL-M-38510 and 6.4 herein.

3.4 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I, and apply over the full recommended operating ambient temperature range.

3.5 Electrical test requirements. The electrical test requirements for each device class shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table III.

3.6 Marking. Marking shall be in accordance with MIL-M-38510. At the option of the manufacturer, marking of the country of origin may be omitted from the body of the microcircuit, but shall be retained on the initial container.

3.6.1. Total dose radiation hardness identifier. Total dose radiation hardness identifier shall be in accordance with MIL-M-38510 and 4.5.4 herein.

3.6.2 Serialization. All class S devices shall be serialized in accordance with MIL-M-38510.

3.6.3 Correctness of indexing and marking. All devices shall be subjected to the final electrical tests specified in table II after part number marking to verify that they are correctly indexed and identified by part number. Optionally, an approved electrical test may be devised especially for this requirement.

3.7 Microcircuit group assignment. The devices covered by this specification shall be in microcircuit group number 37 (see MIL-M-38510, appendix E).

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-M-38510 and methods 5005 and 5007, as applicable, of MIL-STD-883, except as modified herein.

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to qualification and quality conformance inspection. The following additional criteria shall apply:

- a. Delete the sequence specified in 3.1.10 through 3.1.14 of method 5004 and substitute lines 1 through 7 of table II herein.
- b. Burn-in (method 1015 of MIL-STD-883).
 - (1) Static tests (test condition A) using circuit shown on figure 3, or equivalent. Ambient temperature (T_A) shall be $+125^{\circ}\text{C}$ minimum. Test duration for each static test shall be 24 hours minimum for class S devices and in accordance with table I of method 1015 for class B devices.
 - (2) Dynamic test (test condition D) using circuit shown on figure 3, or equivalent. Ambient temperature shall be $+125^{\circ}\text{C}$ minimum. Test duration shall be in accordance with table I of method 1015.
- c. Interim and final electrical parameters shall be as specified in table II herein.
- d. For class S devices, post dynamic burn-in, or class B devices, post static burn-in, electrical parameter measurements may, at the manufacturer's option, be performed separately or included in the final electrical parameter requirements.

4.2.1 Percent defective allowable (PDA).

- a. The PDA for class S devices shall be 5 percent for static burn-in and 5 percent for dynamic burn-in, based on the exact number of devices submitted to each separate burn-in.
- b. Static burn-in I and II failures shall be cumulative for determining the PDA.
- c. The PDA for class B devices shall be in accordance with MIL-M-38510 for static burn-in. Dynamic burn-in is not required.
- d. Those devices whose measured characteristics, after burn-in, exceed the specified delta (Δ) limits or electrical parameter limits specified in table III, subgroup 1, are defective and shall be removed from the lot. The verified failures divided by the total number of devices in the lot initially submitted to burn-in shall be used to determine the percent defective for the lot and the lot shall be accepted or rejected based on the specified PDA.

4.3 Qualification inspection. Qualification inspection shall be in accordance with MIL-M-38510. Inspections to be performed shall be those specified in method 5005 of MIL-STD-883 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.5).

4.4 Quality conformance inspection. Quality conformance inspection shall be in accordance with MIL-M-38510 and as specified herein. Inspections to be performed shall be those specified in method 5005 of MIL-STD-883 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.5).

4.4.1 Group A inspection. Group A inspection shall be in accordance with table I of method 5005 of MIL-STD-883 and as follows:

- a. Tests shall be performed in accordance with table II herein.
- b. Subgroups 5, 6, 7, and 8 of table I of method 5005 of MIL-STD-883 shall be omitted.
- c. Subgroup 4 (C_1 measurement) shall be measured only for initial qualification and after process or design changes which may affect input capacitance. Capacitance shall be measured between the designated terminal and V_{SS} at a frequency of 1 MHz.
- d. Subgroups 9 and 11 shall be measured only for initial qualification and after process or design changes which may affect dynamic performance.

4.4.2 Group B inspection. Group B inspection shall be in accordance with table II of method 5005 of MIL-STD-883 and as follows:

- a. Class S steady-state life test circuits shall be submitted to the qualifying activity for approval. When the alternate steady-state life test is used, the circuit on figure 3, or equivalent, shall be used.
- b. Electrostatic Discharge Sensitivity (ESDS) testing shall be performed in accordance with MIL-STD-883, method 3015. The option to categorize devices as ESD sensitive without performing the test is not allowed. Device types categorized as ESD sensitive shall be further tested using method 3015 modified as follows:
 - (1) Table I pin combinations 4 and 5 shall be deleted.
 - (2) The test sequence specified in paragraph 3.b shall be repeated an additional four times rather than the two specified.
 - (3) Only those device types that pass ESDS testing at 1,000 volts or greater shall be considered as conforming to the requirements of this specification.
- c. End-point electrical parameters shall be as specified in table II herein. Delta limits shall apply only to subgroup 5 of group B inspections and shall consist of tests specified in table IV herein.

4.4.3 Group C inspection. Group C inspection shall be in accordance with table III of method 5005 of MIL-STD-883 and as follows:

- a. End-point electrical parameters shall be as specified in table II herein. Delta limits shall apply only to subgroup 1 of group C inspection and shall consist of tests specified in table IV herein.
- b. Steady-state life test (method 1005 of MIL-STD-883) conditions:
 - (1) Test condition D and as specified in 4.5.2 herein and as shown on figure 3 (note 3), or equivalent.
 - (2) $T_A = +125^\circ\text{C}$ minimum.
 - (3) Test duration, 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

Text continues on page 77.

TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions 1/ $T_C = +125^\circ C$ unless otherwise specified	Device type 2/	V _{CC}	Limits		
					Min	Max	Unit
High-level output voltage	V _{OH1} 3/	V _{IH} = 1.5 V V _{IL} = 0.3 V I _{OH} = -20 μA	01-09	2.0 V	1.95	---	V
	V _{OH2} 3/	V _{IH} = 3.15 V V _{IL} = 0.9 V I _{OH} = -20 μA	01-09	4.5 V	4.44	---	V
	V _{OH3}	V _{IH} = 4.2 V V _{IL} = 1.2 V I _{OH} = -20 μA	01-09	6.0 V	5.95	---	V
	V _{OH4} 3/	V _{IH} = 3.15 V V _{IL} = 0.9 V I _{OH} = -6.0 mA	01-09	4.5 V	3.7	---	V
	V _{OH5}	V _{IH} = 4.2 V V _{IL} = 1.2 V I _{OH} = -7.8 mA	01-09	6.0 V	5.2	---	V
	V _{OH6}	V _{IH} = 2.0 V V _{IL} = 0.8 V I _{OH} = -20 μA	53	4.5 V	4.4	---	V
	V _{OH7}	V _{IH} = 2.0 V V _{IL} = 0.8 V I _{OH} = -6.0 mA	53	5.5 V	3.7	---	V
Low-level output voltage	V _{OL1} 3/	V _{IL} = 0.8 V V _{IH} = 1.5 V I _{OL} = 20 μA	01-09	2.0 V	---	0.05	V
	V _{OL2} 3/	V _{IL} = 0.9 V V _{IH} = 3.15 V I _{OL} = 20 μA	01-09	4.5 V	---	0.05	V
	V _{OL3}	V _{IL} = 1.2 V V _{IH} = 4.2 V I _{OL} = 20 μA	01-09	6.0 V	---	0.05	V
	V _{OL4} 3/	V _{IL} = 0.9 V V _{IH} = 3.15 V I _{OL} = +6.0 mA	01-09	4.5 V	---	0.4	V
	V _{OL5}	V _{IL} = 1.2 V V _{IH} = 4.2 V I _{OL} = 7.8 mA	01-09	6.0 V	---	0.4	V

See footnotes at end of table.

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions 1/ $T_C = +125^\circ C$ unless otherwise specified	Device type 2/	V _{CC}	Limits		
					Min	Max	Unit
Low-level output voltage	V _{OL6}	V _{IH} = 2.0 V V _{IL} = 0.8 V I _{OH} = +20 μ A	53	4.5 V	---	0.05	V
	V _{OL7}	V _{IH} = 2.0 V V _{IL} = 0.8 V I _{OH} = +6.0 mA					
Positive input clamp voltage	V _{IC+}	V _{CC} = GND I _{IN} = +1 mA $T_C = +25^\circ C$	A11	---	8/	+1.5	V
Negative input clamp voltage	V _{IC-}	V _{CC} = Open I _{IN} = -1 mA $T_C = +25^\circ C$	A11	---	---	-1.5	V
Control input current low	I _{IL}	V _{IN} = GND	01-09 53	6.0 V 5.5 V	---	-0.1	μ A
	I _{IH}	V _{IN} = V _{CC}		6.0 V 5.5 V		-0.1	μ A
Input/output current, low-level, outputs disabled	I _{IL} / I _{OZL} 4/	V _{IN} control = 4.2 V or 1.2 V V _{OUT} = GND	01-09	6.0 V	---	-2.0	μ A
		V _{IN} control = 2.0 V or 0.8 V V _{OUT} = GND	53	5.5 V		-2.0	μ A
Input/output current, high-level, outputs disabled	I _{IH} / I _{OZH} 4/	V _{IN} control = 4.2 V or 1.2 V V _{OUT} = 6 V	01-09	6.0 V	---	2.0	μ A
		V _{IN} control = 2.0 V or 0.8 V V _{OUT} = 5.5 V	53	5.5 V		2.0	μ A
Short circuit output current	I _{OS1} 3/	$T_C = -55^\circ C$ to $+125^\circ C$ V _O = GND V _I = GND or V _{CC}	01-09	2.0 V	-2	-60	μ A
	I _{OS2} 3/		A11	4.5 V	-15	-165	
	I _{OS3} 3/		01-09	6.0 V	-25	-210	
	I _{OS4}		A11	4.0 V	-10	-135	
	I _{OS5} 3/		53	5.5 V	-25	-210	

See footnotes at end of table.

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions 1/ $T_C = +125^\circ\text{C}$ unless otherwise specified	Device type 2/	V_{CC}	Limits		
					Min	Max	Unit
Supply current quiescent	I_{CC}	$V_I = 6.0 \text{ V}$	01,02, 03,06,07, 08,09	6.0 V	---	20	μA
				53	5.5 V	---	20 μA
	I_{CCZ}	$V_I = 6.0 \text{ V}$	01,02 03,06,07, 08,09	6.0 V	---	10	μA
				53	5.5 V	---	10 μA
Additional supply current quiescent per input pin (one unit load)	I_{CCA} 9/	$V_{IL} = 0.8 \text{ V}$ $V_{IH} = 2.4 \text{ V}$ Test pin at $V_{IN} = 2.4 \text{ V}$ Other pins at 0.8 V or 5.5 V $I_o = 0 \text{ V}$	53	5.5 V		1.5	mA
Maximum clock frequency	f_{MAX}	$V_I = 0-V_{CC}, 50\% \text{ DC}$ $C_L = 50 \text{ pF} \pm 10\%$ 5/	08,09	4.5 V	23	---	MHz
Control capacitance	C_C	$T_C = +25^\circ\text{C}$	A11		---	10	pF
Input/output capacitance	$C_{I/O}$	$T_C = +25^\circ\text{C}$	A11		---	20	pF
Power dissipation capacitance	C_{PD} 2/ 3/	$T_C = +25^\circ\text{C}$	01,02, 03,53, 04,05, 06,07, 08,09		---	70	pF
					---	40	
					---	120	
					---	55	
Transition delay times 6/, 7/	$t_{THL},$ t_{TLH}	$V_{CC} = 4.5 \text{ V}$ $C_L = 50 \text{ pF} \pm 10\%$	A11	4.5 V	2	16	ns
Propagation delay time, clock to bus	$t_{PLH1},$ t_{PHL1}		08 09	4.5 V	8	51	ns
				4.5 V	8	56	ns
Propagation delay time, bus to bus	$t_{PLH2},$ t_{PHL2}		01, 02, 03,53 06,07, 08,09	4.5 V	3	23	ns
				4.5 V	4	23	ns
				4.5 V	4	33	ns
				4.5 V	4	26	ns
				4.5 V	5	40	ns
Propagation delay time, select (with bus input high) to bus	$t_{PLH3},$ t_{PHL3}		08,09	4.5 V	10	51	ns

See footnotes at end of table.

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions ^{1/} $T_C = +125^\circ C$ unless otherwise specified	Device type ^{2/}	V _{CC}	Limits		
					Min	Max	Unit
Propagation delay time, select (with bus input low) to bus	t _{PLH4} , t _{PHL4}	V _{CC} = 4.5 V $C_L = 50 \text{ pF} \pm 10\%$	08,09	4.5 V	10	51	ns
Propagation delay time, disabled-to-high level output	t _{ZH1}	$V_{CC} = 4.5 \text{ V}$ $C_L = 50 \text{ pF} \pm 10\%$ $R_L = 1 \text{ k}\Omega \pm 5\%$ <u>6/</u> , <u>7/</u>	01	4.5 V	4	35	ns
			02	4.5 V	4	36	ns
			03	4.5 V	9	59	ns
			53	4.5 V	6	54	ns
Propagation delay time, disabled-to-high level output, enable to bus	t _{ZH2}		06,07,	4.5 V	9	59	ns
			08,09	4.5 V	6	57	ns
Propagation delay time, disabled-to-high level output direction to bus	t _{ZH3}		08,09	4.5 V	6	57	ns
Propagation delay time, disabled-to-low level output	t _{ZL1}		01	4.5 V	4	35	ns
			02	4.5 V	4	36	ns
			03	4.5 V	9	59	ns
			53	4.5 V	6	54	ns
Propagation delay time, disabled-to-low level, output enable to bus	t _{ZL2}		06,07,	4.5 V	9	59	ns
			08,09	4.5 V	6	57	ns
Propagation delay time, disabled-to-low level, direction to bus	t _{ZL3}		08,09	4.5 V	6	57	ns
Propagation delay time, high-level to disabled output	t _{PHZ1}		01	4.5 V	4	40	ns
			02	4.5 V	4	42	ns
			03	4.5 V	8	54	ns
			53	4.5 V	6	54	ns
Propagation delay time, high-level-to-disabled output enable to bus	t _{PHZ2}		06,07,	4.5 V	8	53	ns
			08,09	4.5 V	6	57	ns
Propagation delay time, high-level-to-disabled, output direction to bus	t _{PHZ3}		08,09	4.5 V	6	57	ns
Propagation delay time, low-level-to-disabled output	t _{PLZ1}		01	4.5 V	4	40	ns
			02	4.5 V	4	42	ns
			03	4.5 V	8	54	ns
			53	4.5 V	6	54	ns

See footnotes at end of table.

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions ^{1/} $T_C = +125^\circ C$ unless otherwise specified	Device type ^{2/}	V _{CC}	Limits		Unit
					Min	Max	
Propagation delay time, low-level-to-disabled output, enable to bus	t _{PLZ2}	$V_{CC} = 4.5 V$ $C_L = 50 \mu F \pm 10\%$ $R_L = 1 k\Omega \pm 5\%$ ^{6/} , ^{7/}	06,07, 08,09	4.5 V	8	53	ns
Propagation delay time, low-level-to-disabled output, direction to bus	t _{PLZ3}		08,09	4.5 V	6	57	ns

- 1/ Complete terminal conditions shall be as specified in table III.
- 2/ Power dissipation capacitance (C_{pp}) typically per transceiver.
- 3/ Guaranteed but not tested.
- 4/ I_{OZL} = output set to high state. Three state output conditions are required.
 I_{OZH} = output set to low state. Three state output conditions are required.
- 5/ Tested at $V_{CC} = 4.5 V$ at $+125^\circ C$ for sample testing and $V_{CC} = 4.5 V$ at $+25^\circ C$ for screening.
Guaranteed at other V_{CC} voltages and temperatures, see table IB and exception in 4.4.1d.
- 6/ Tested at $V_{CC} = 4.5 V$ at $+125^\circ C$ for sample testing and $V_{CC} = 4.5 V$ at $+25^\circ C$ for screening.
Guaranteed at other V_{CC} voltages and temperatures, see table IA and exception in 4.4.1d.
- 7/ For propagation and transition delay times at $V_{CC} = 2.0 V$, increase limit by a factor of 5.
For propagation and transition delay times at $V_{CC} = 6.0 V$, decrease limit by a factor of .85.
- 8/ A minimum limit of 0.4 V applies only when test equipment limitations do not allow the GND pin to be open during testing.
- 9/ Total supply current = $I_{CC} + I_{CCA}$.

TABLE IA. Calculated dynamic figures at -55/+25 ambient temperature (°C).

V_{CC}	$T_A = ({}^\circ C)$	
	+125	-55/+25
2.0 V	5X	5Y
4.5 V	$X = 1$	$0.75X = Y$
6.0 V	0.85X	0.85Y

Normalized numbers
(+125 °C equals 1)

NOTE: The 2.0 V and 6.0 V numbers are derived from their 4.5 V integer value.
Rounding off according 5/4.

TABLE IB. Calculated formula for f_{MAX} at -55/+25 ambient temperature.

V_{CC}	$T_A = ({}^\circ C)$	
	+125	-55/+25
2.0 V	0.2X	0.2Y
4.5 V	$X = 1$	$1.33X = Y$
6.0 V	1.18X	1.18Y

Normalized numbers
(+125 °C equals 1)

NOTE: The 2.0 V and 6.0 V numbers are derived from their 4.5 V integer value.
Rounding off according 5/4.

TABLE II. Burn-in and electrical test requirements.

Line no.	Applicable tests and MIL-STD-883 test method	Class S device 1/				Class B device 1/			
		Ref. paragraph	Table III subgroups 2/	Table IV delta limits 3/	Test circuit figure	Ref. paragraph	Table III subgroups 2/	Table IV delta limits 3/	Test circuit figure
1	Interim electrical parameters (method 5004)		1				1		
2	Static burn-in I (method 1015)	4.2b 4.5.2	Req'd		3		Not req'd		
3	Same as line 1		1	Δ					
4	Static burn-in II (method 1015)	4.2b 4.5.2	Req'd		3	4.2b 4.5.2	4/ Req'd		3
5	Same as line 1	4.2d	1*	Δ		4.2d	1* 4/	Δ	
6	Dynamic burn-in (method 1015)	4.2b 4.5.2	Req'd		1/		Not req'd		
7	Same line 1	4.2d	1	Δ					
8	Final electrical parameters (method 5004)		1*,2,3, 7,8,9				1*,2,7,9 4/		
9	Group A test requirements (method 5005)	4.4.1	1,2,3,4, 7,8,9, 10,11			4.4.1	1,2,3,4, 7,8,9, 10,11		
10	Group B end-point electrical parameters (method 5005)	4.4.2	1,2,3,9, 10,11 5/	Δ			1		
11	Group C end-point electrical parameters (method 5005)					4.4.3	1,2	Δ	
12	Group D end-point electrical parameters (method 5005)	4.4.4	1,2,3			4.4.4	1,2		

1/ Blank spaces indicate tests are not applicable.

2/ * indicates PDA applies to subgroup 1 (see 4.2.1).

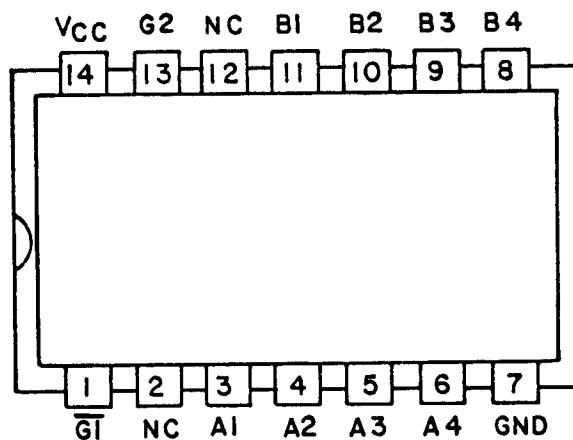
3/ Δ indicates delta limit shall be required only on table III subgroup 1, where specified, and the delta values shall be computed with reference to the previous interim electrical parameters (line 1).

4/ The device manufacturer may at his option either complete subgroup 1 electrical parameter measurements, including delta measurements, within 96 hours after burn-in completion (removal of bias); or may complete subgroup 1 electrical measurements without delta measurements within 24 hours after burn-in completion (removal of bias).

5/ indicates also applies to electrostatic discharge sensitivity tests.

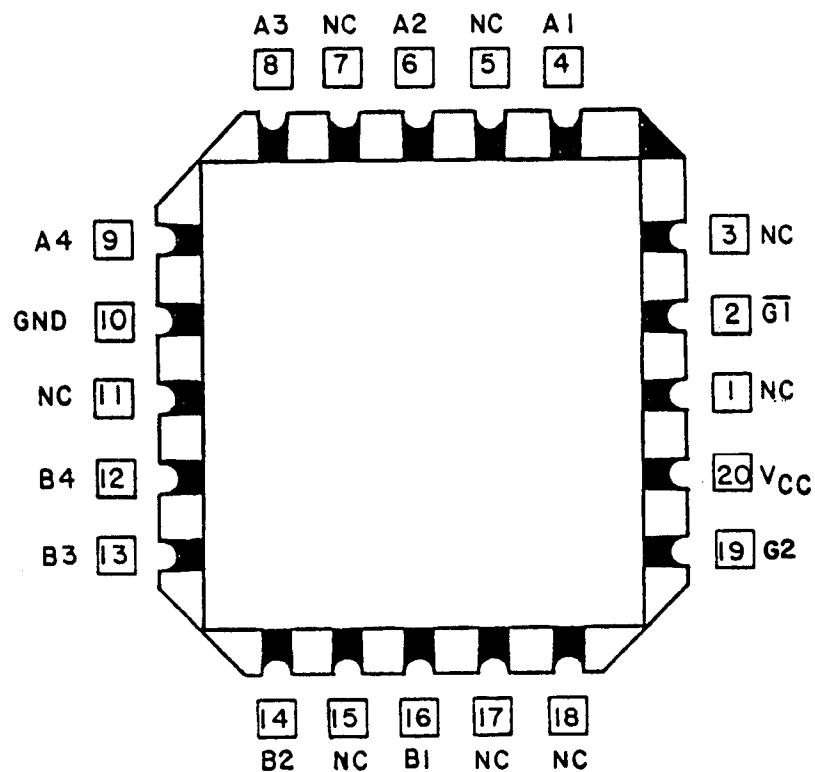
Device types 01 and 02

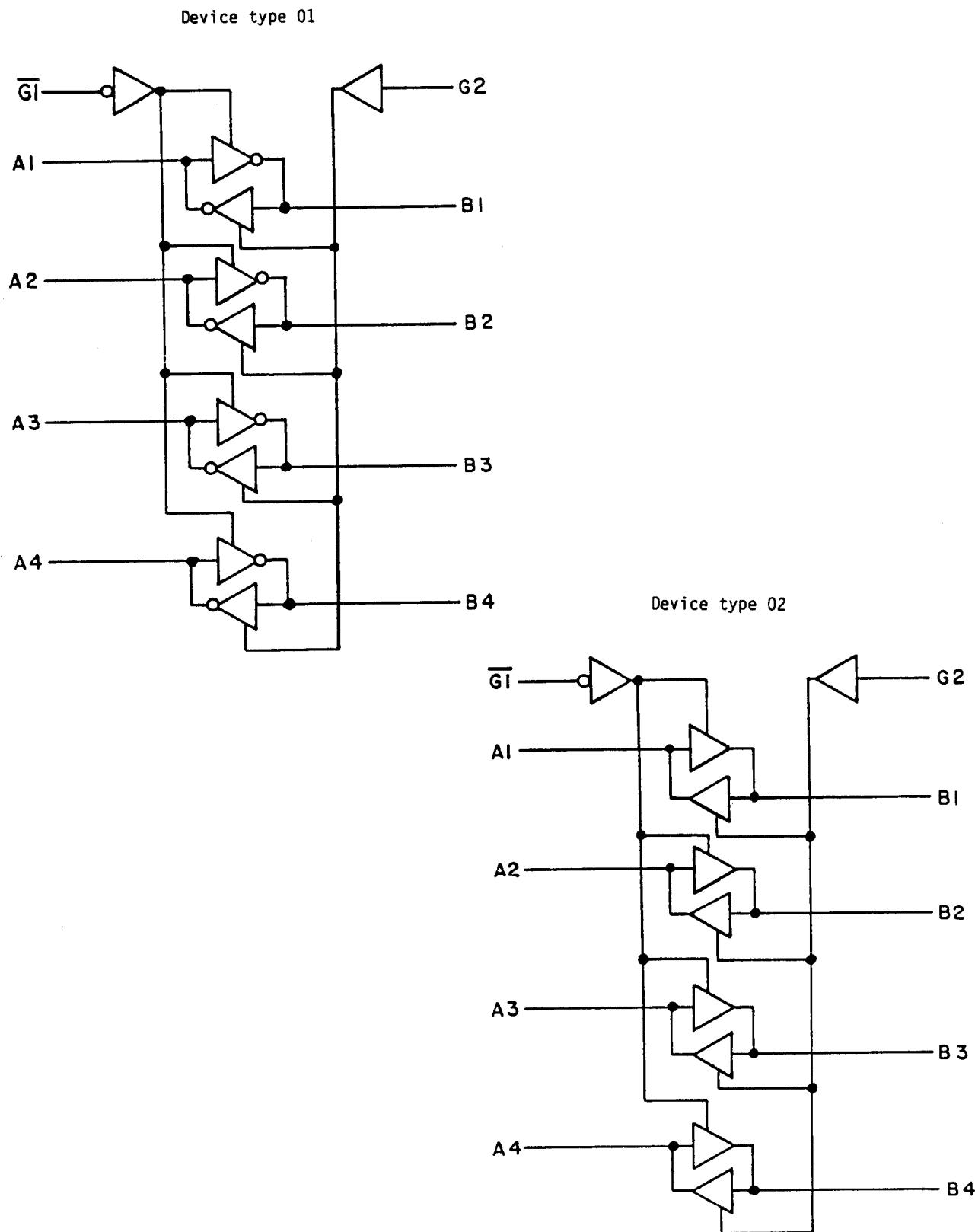
Case C



Device types 01 and 02

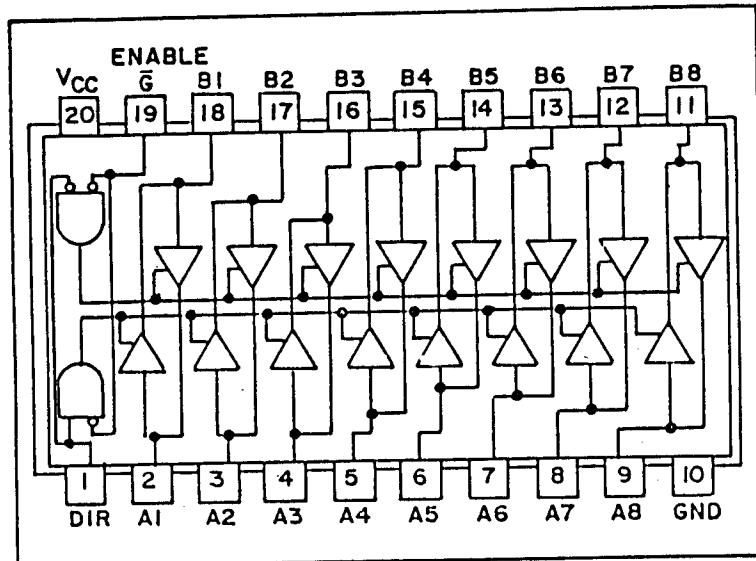
Case 2

FIGURE 1. Logic diagrams and terminal connections (top view).

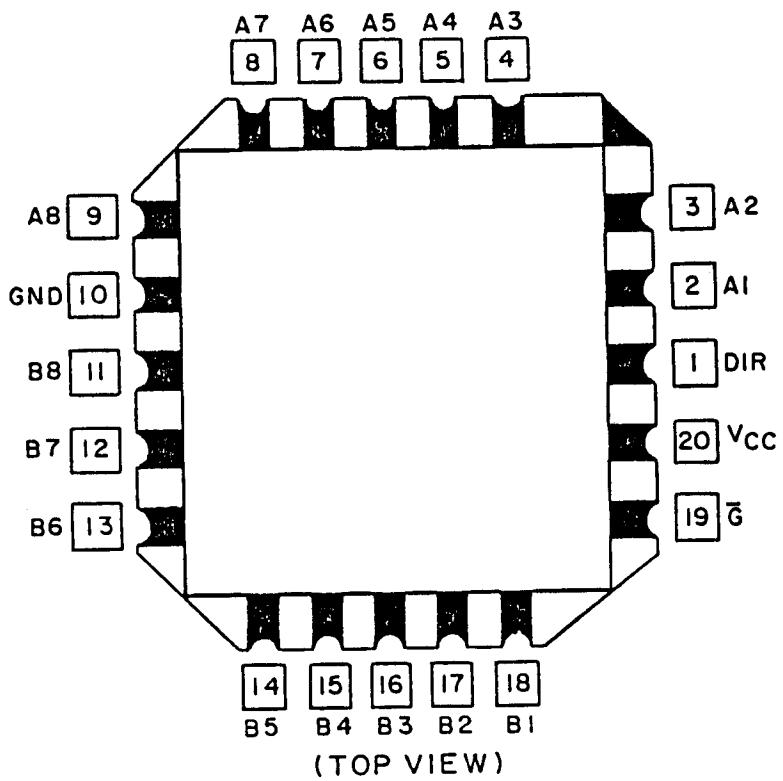
FIGURE 4. Switching time test circuit and waveforms - Continued.

Device types 03 and 53

Cases R

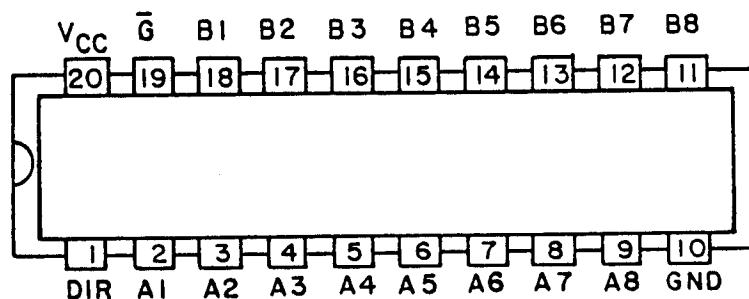
Device types 03 and 53

Case 2

FIGURE 1. Logic diagrams and terminal connections (top view) - Continued.

Device types 06, 07

Case R



Device types 06, 07

Case 2

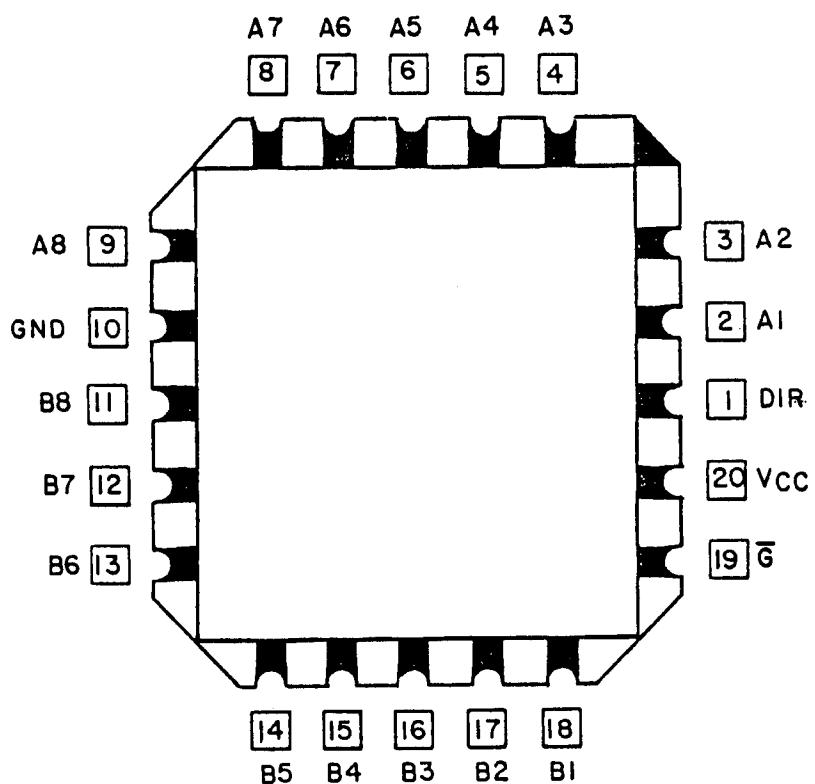
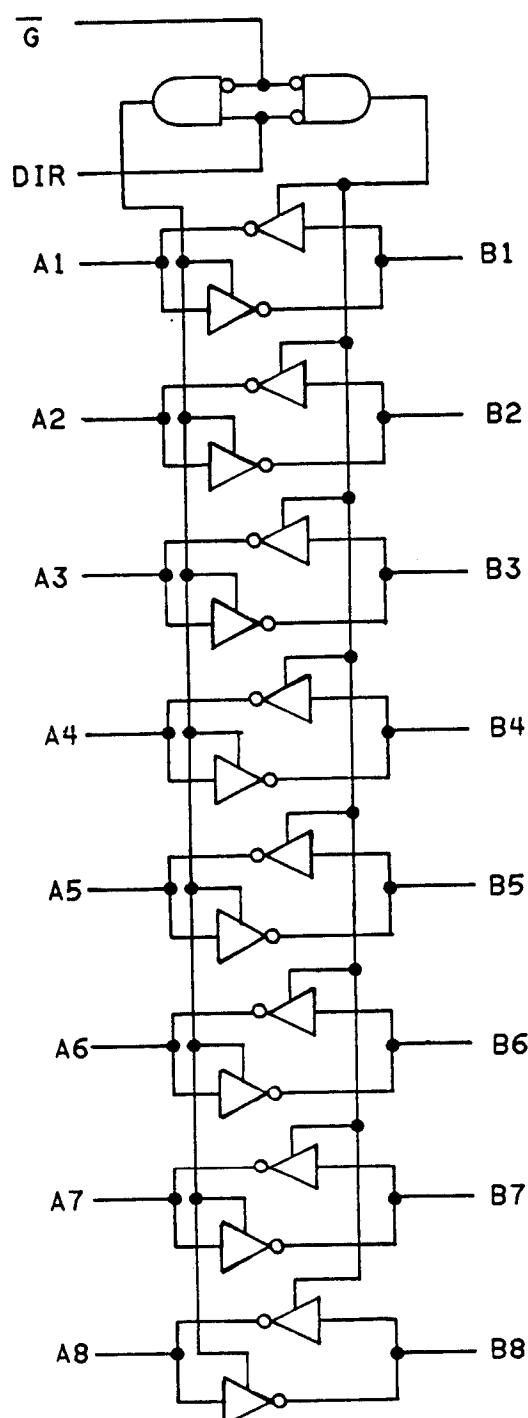
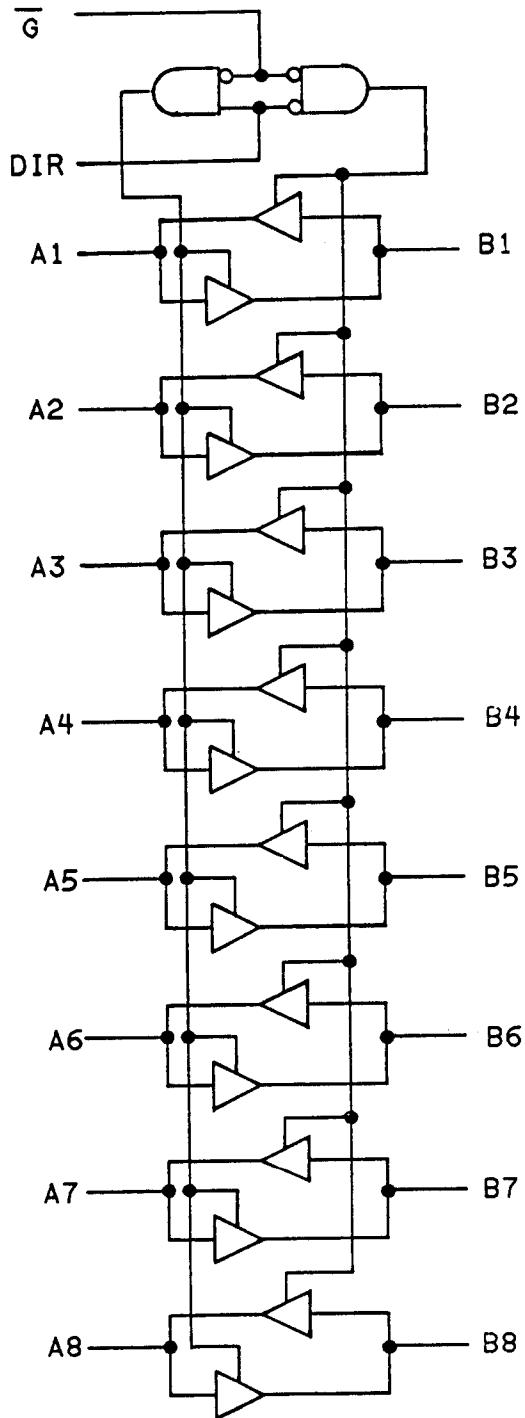


FIGURE 1. Logic diagrams and terminal connections (top view) - Continued.

Device type 06

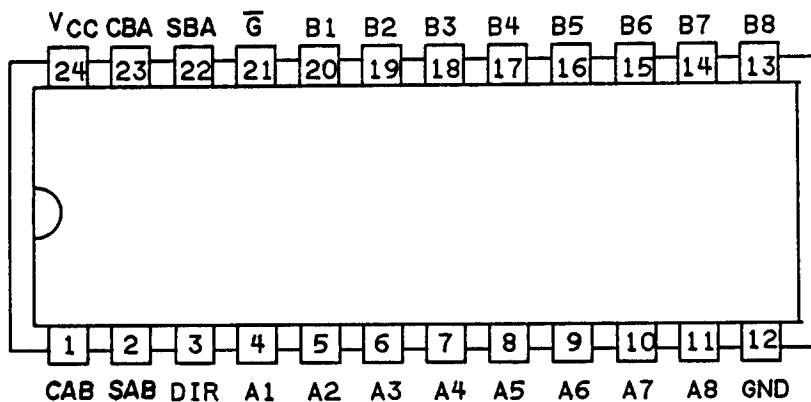


Device type 07

FIGURE 1. Logic diagrams and terminal connections (top view) - Continued.

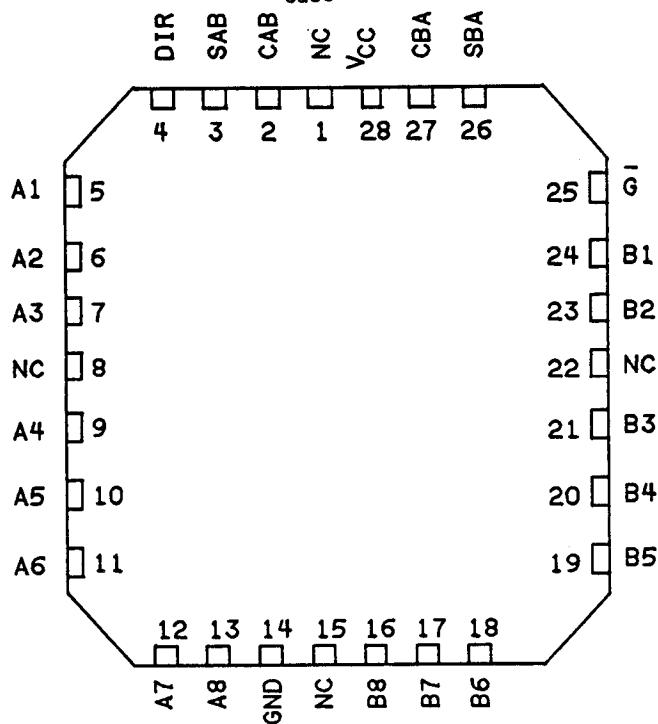
Device types 08 and 09
 (Terminal connections)

Case L



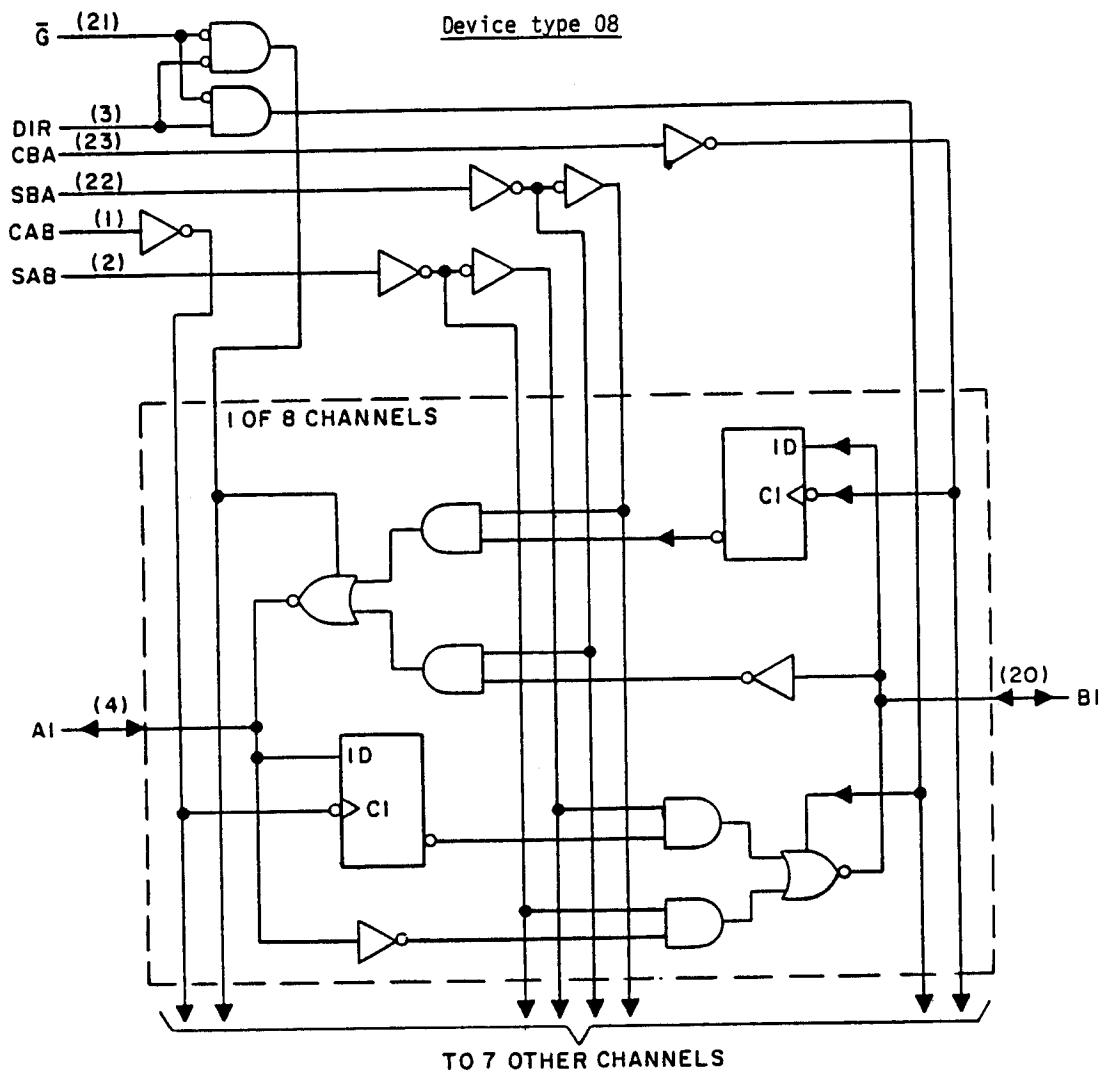
Device types 08 and 09
 (Top view)

Case 3



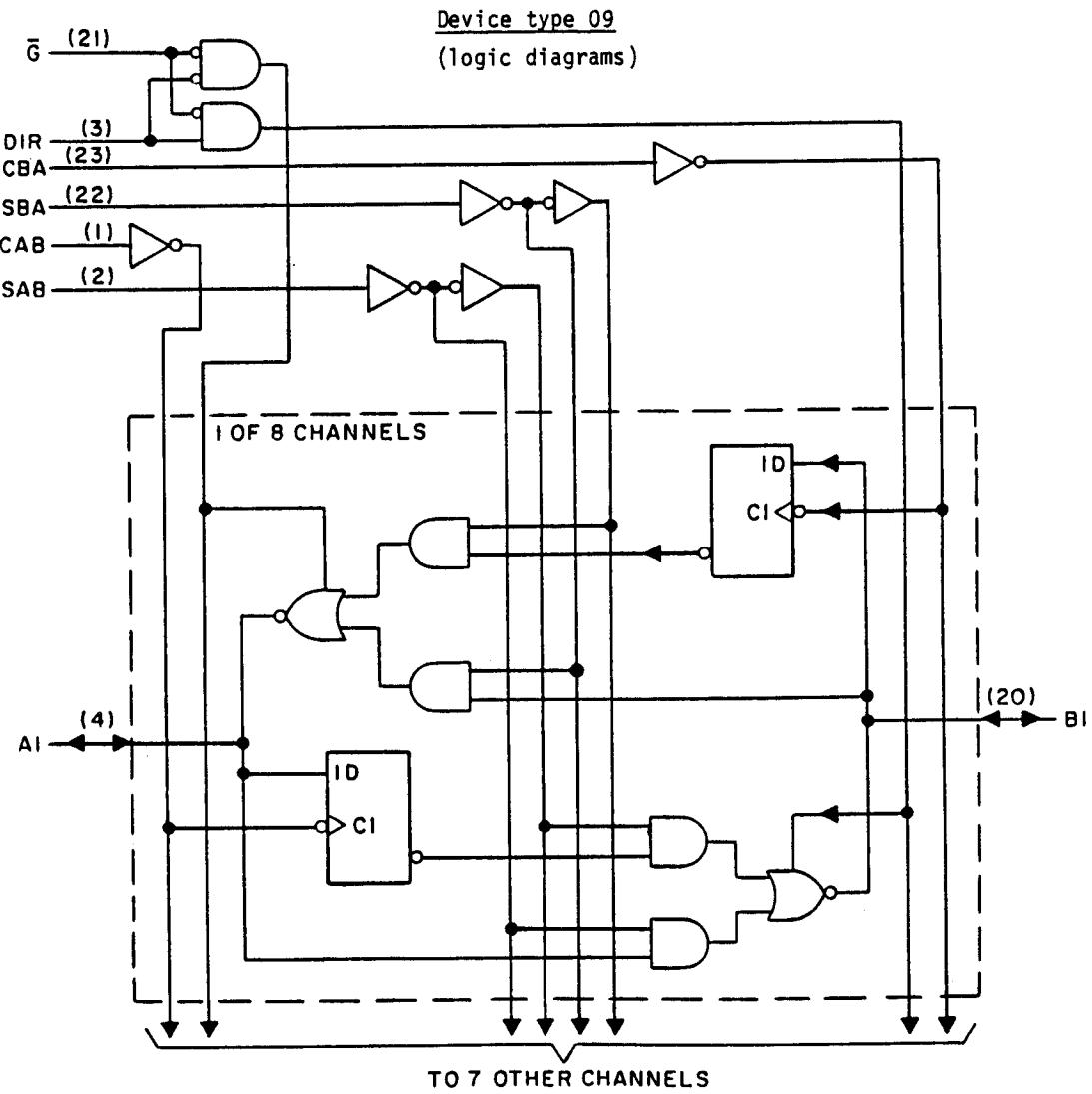
NC-NO internal connection

FIGURE 1. Logic diagrams and terminal connections (top view) - Continued.



NOTE: Terminal connections shown in parentheses are for case L.

FIGURE 1. Logic diagrams and terminal connections (top view) - Continued.



NOTE: Terminal connections shown in parentheses are for case L.

FIGURE 1. Logic diagrams and terminal connections (top view) - Continued.

Device type 01

Inputs		Outputs
\bar{G}_1	G_2	
L	L	\bar{A} to B
H	H	\bar{B} to A
H	L	Isolation
L	H	Isolation

H = high level, L = low level

Device type 02

Inputs		Outputs
\bar{G}_{AB}	G_{BA}	
L	L	A to B
H	H	B to A
H	L	Isolation
L	H	Isolation

H = high level, L = low level

Device types 03 and 53

Enable \bar{G}	Direction control DIR	Operation
L	L	B data to A bus
L	H	A data to B bus
H	X	Isolation

H = high level, L = low level, X = irrelevant

FIGURE 2. Truth tables.

Device type 06

Enable \bar{G}	Direction control DIR	Operation
L	L	\bar{B} data to A bus
L	H	\bar{A} data to B bus
H	X	Isolation

H = High level, L = Low level, X = Irrelevant

Device type 07

Enable \bar{G}	Direction control DIR	Operation
L	L	B data to A bus
L	H	\bar{A} data to B bus
H	X	Isolation

H = High level, L = Low level, X = Irrelevant

FIGURE 2. Truth tables - Continued.

Device type 08

Inputs				Data I/O*		Operation or function	
G	DIR	CAB	CAB	SAB	SBA	A1 thru A8	B1 thru B8
H H	X X	H or L X	H or L X	X X	X X	Input	Input
L L	L L	X X	X H or L	X X	L H	Output	Input
L L	H H	X H or L	X X	L H	X X	Input	Output
X X	X X	+ X	X +	X X	X X	Input not specified	Not specified input
							Store A, B undefined Store B. A undefined

H = High Level L = Low Level X = Irrelevant + = Low-to-high level transition

*The data output functions may be enabled or disabled by various signals at the G and DIR inputs. Data input functions are always enabled, i.e., data at the bus pins will be stored on every low-to-high transition on the clock inputs.

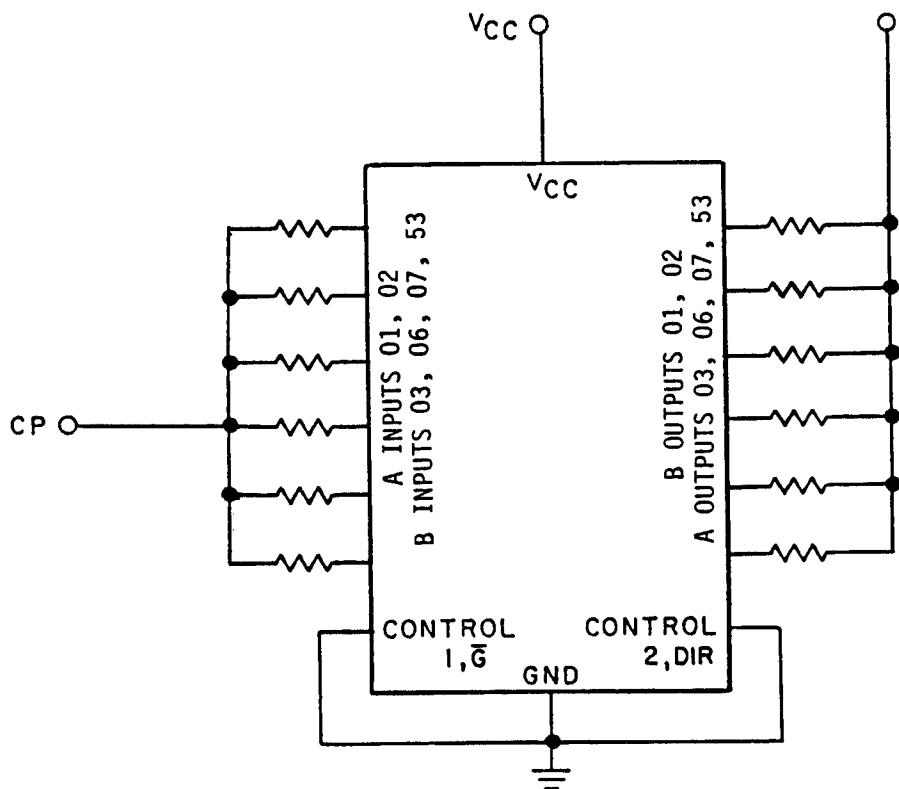
Device type 09

Inputs				Data I/O*		Operation or function	
G	IDIR	CAB	CAB	SAB	SBA	A1 thru A8	B1 thru B8
H H	X X	H or L X	H or L X	X X	X X	Input	Input
L L	L L	X X	X H or L	X X	L H	Output	Input
L L	H H	X H or L	X X	L H	X X	Input	Output
X X	X X	+ X	X +	X X	X X	Input not specified	Not specified input
							Store A, B undefined Store B. A undefined

H = High Level L = Low Level X = Irrelevant + = Low-to-high level transition

*The data output functions may be enabled or disabled by various signals at the G and DIR inputs. Data input functions are always enabled, i.e., data at the bus pins will be stored on every low-to-high transition on the clock inputs.

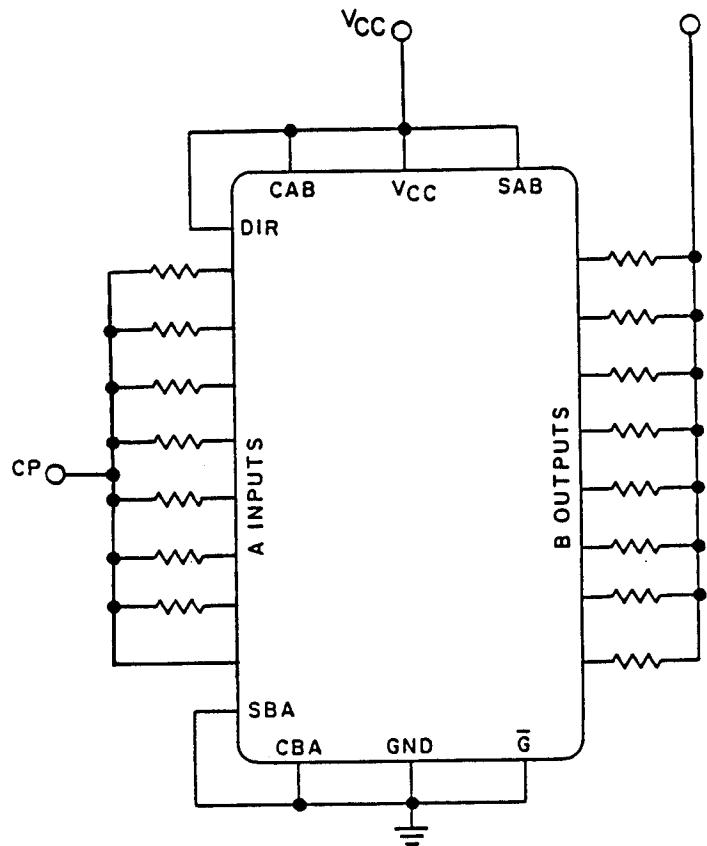
FIGURE 2. Truth tables - Continued.

Device types 01, 02, 03, 06, 07 and 53

NOTES:

1. For static burn-in I, all inputs shall be connected to GND. Outputs shall be open or connected to $V_{CC}/2$. Resistors are optional on outputs if open. Resistors are required on inputs, and required on outputs connected to $V_{CC}/2$. $R = 680\Omega$ to $47\text{ k}\Omega$.
2. For static burn-in II, all inputs shall be connected through the resistors to V_{CC} . Outputs shall be open or connected to $V_{CC}/2$. Resistors are optional on outputs if open. Resistors are required on inputs, and required on outputs connected to $V_{CC}/2$.
 $R = 680\Omega$ to $47\text{ k}\Omega$.
3. For dynamic burn-in, all inputs shall be connected through the resistors in parallel to a common CP. Outputs shall be connected to $V_{CC}/2 \pm .5\text{ V}$ through the resistors.
 $R = 680\Omega \pm 5\%$ for outputs, 680Ω to $47\text{ k}\Omega$ for inputs.
4. CP = 25 kHz to 1 MHz square wave; duty cycle = $50 \pm 15\%$; $V_{IH} = 4.5\text{ V}$ to V_{CC} ; $V_{IL} = 0 \pm .5\text{ V}$, transition time $\leq 0.5\text{ }\mu\text{s}$.
5. $V_{CC} = 6.0\text{ V} \pm 0.5\text{ V}$.

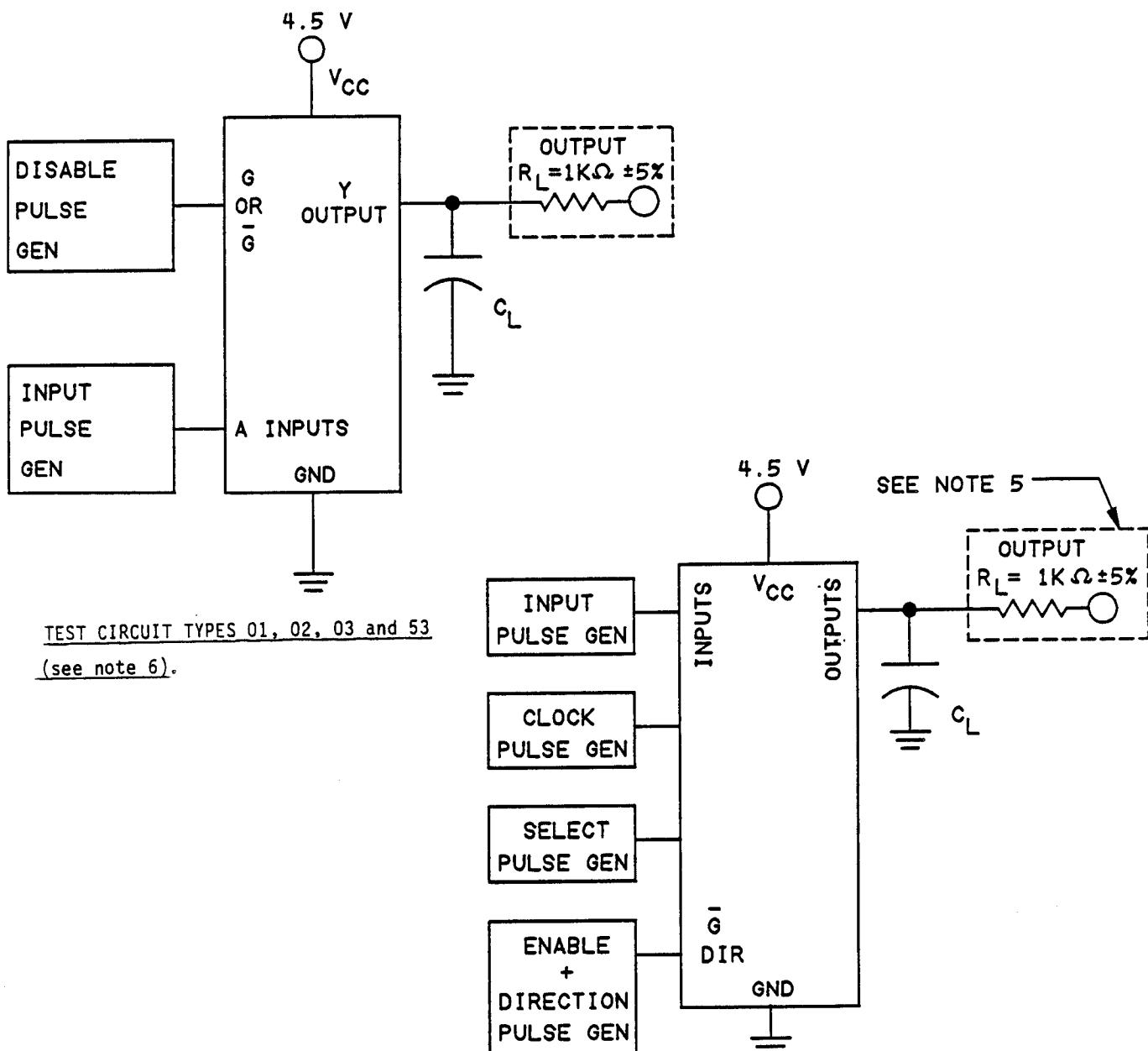
FIGURE 3. Burn-in and life test circuits.

Device types 08 and 09

NOTES:

1. For static burn-in I, all inputs shall be connected to GND. Outputs shall be open or connected to $V_{CC}/2$. Resistors are optional on outputs if open. Resistors are required on inputs, and required on outputs connected to $V_{CC}/2$. $R = 680\Omega$ to $47\text{ k}\Omega$.
2. For static burn-in II, all inputs shall be connected through the resistors to V_{CC} . Outputs shall be open or connected to $V_{CC}/2$. Resistors are optional on outputs if open. Resistors are required on inputs, and required on outputs connected to $V_{CC}/2$.
 $R = 680\Omega$ to $47\text{ k}\Omega$.
3. For dynamic burn-in, all inputs shall be connected through the resistors in parallel to a common CP. Outputs shall be connected to $V_{CC}/2 \pm .5\text{ V}$ through the resistors.
 $R = 680\Omega \pm 5\%$ for outputs, 680Ω to $47\text{ k}\Omega$ for inputs.
4. CP = 25 kHz to 1 MHz square wave; duty cycle = $50 \pm 15\%$; $V_{IH} = 4.5\text{ V}$ to V_{CC} ; $V_{IL} = 0 \pm .5\text{ V}$, transition time $\leq 0.5\text{ }\mu\text{s}$.
5. $V_{CC} = 6.0\text{ V} \pm 0.5\text{ V}$.

FIGURE 3. Burn-in and life test circuits - Continued.

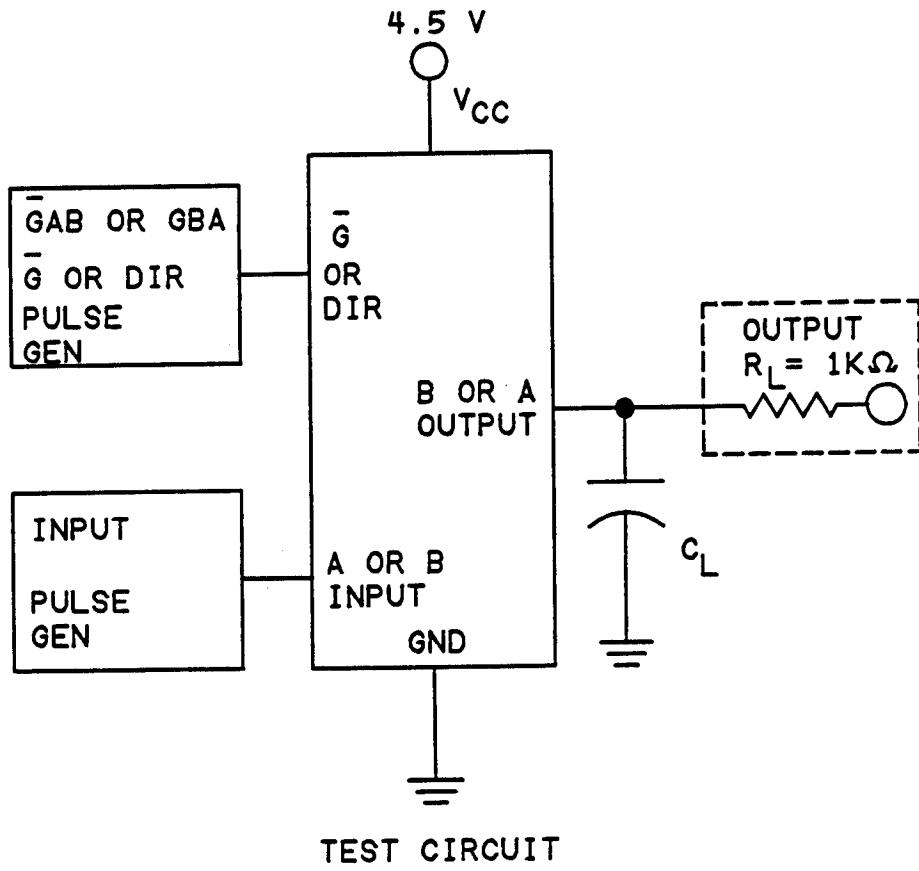


NOTES:

1. $R_L = 1k\Omega \pm 5\%$.
2. $C_L = 50 \text{ pF} \pm 10\%$ including probe and jig capacitance.
3. The pulse generators have the following characteristics:
 $V_{gen} = 4.5 \text{ V}$, $\text{PRR} \leq 1 \text{ MHz}$, $t_{TLH} \leq 6 \text{ ns}$, $t_{THL} \leq 6 \text{ ns}$, $Z_{OUT} = 50\Omega$.
4. Clock pulse characteristics: $t_p (\text{CLK}) = 18 \text{ ns}$, $t_{setup} = 20 \text{ ns}$, $t_{hold} = 5 \text{ ns}$.
5. Output connected to V_{CC} for t_{PLZ} and t_{PZL} ; and to GND for t_{PHZ} and t_{PZH} , see figure 4.
6. The input signal for the 53 device type (HCT) will be 0-3 volts; however, the 50% V_{CC} measure point is 1.3 volts for input and output signals. The 10% V_{CC} and 90% V_{CC} points are, 3 V and 2.7 V, respectively.

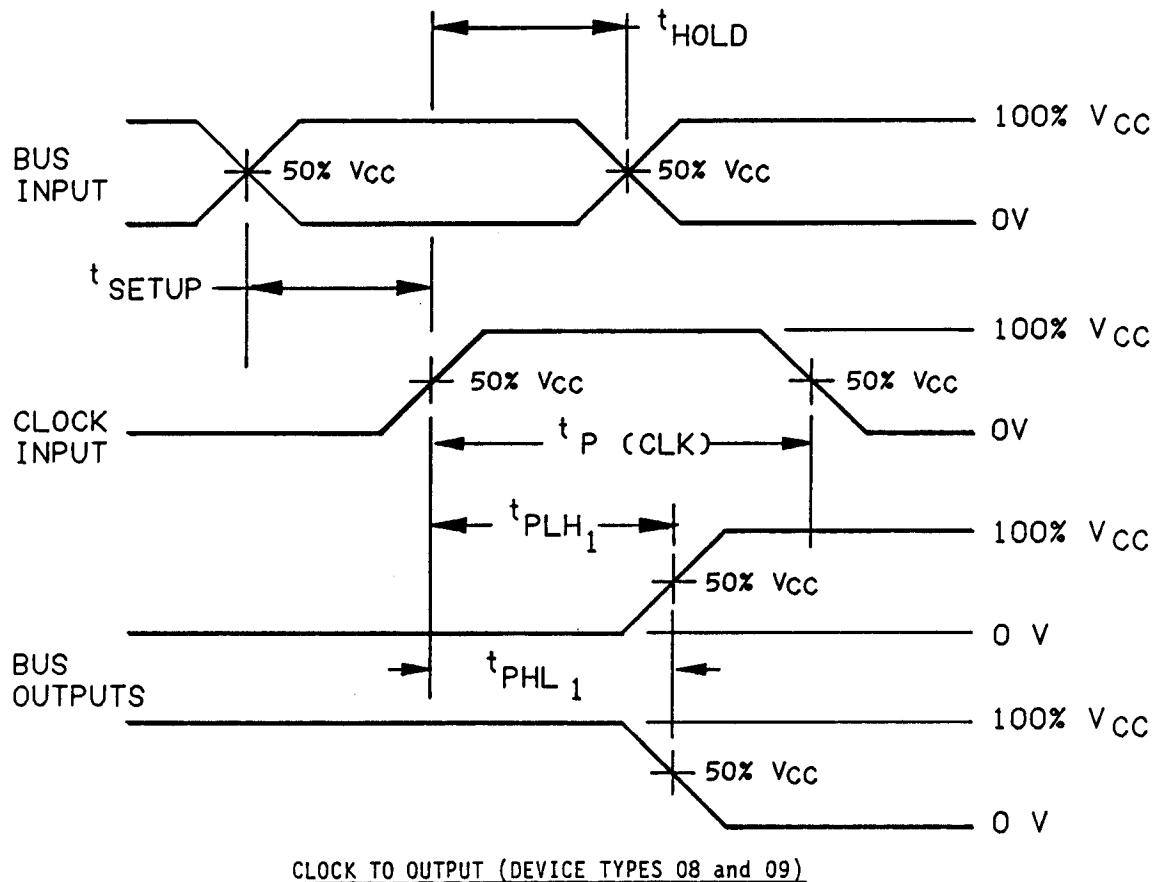
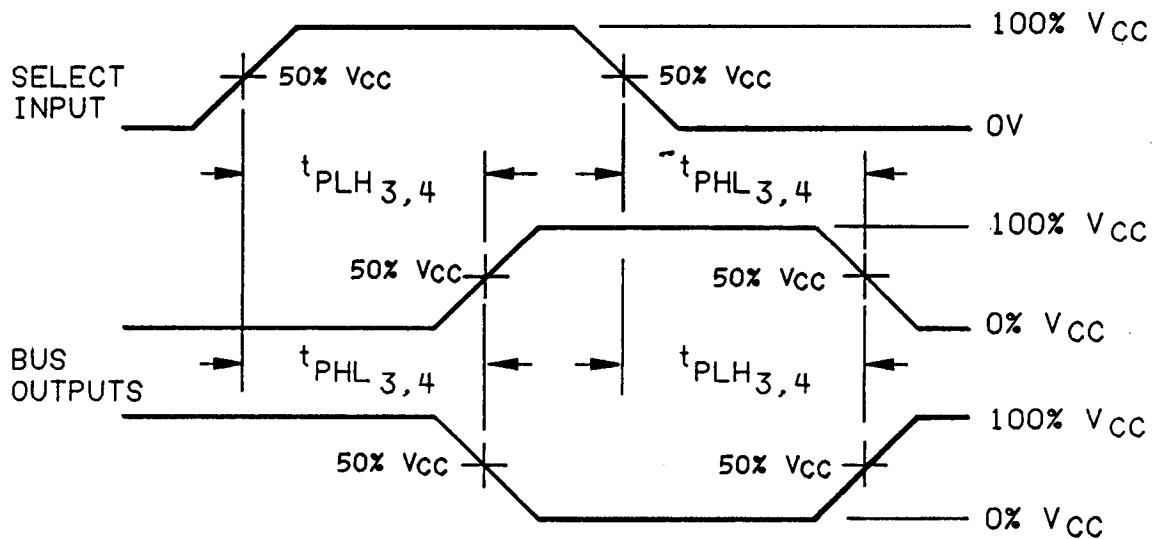
FIGURE 4. Switching time test circuit and waveforms.

Device types 06 and 07

**NOTES:**

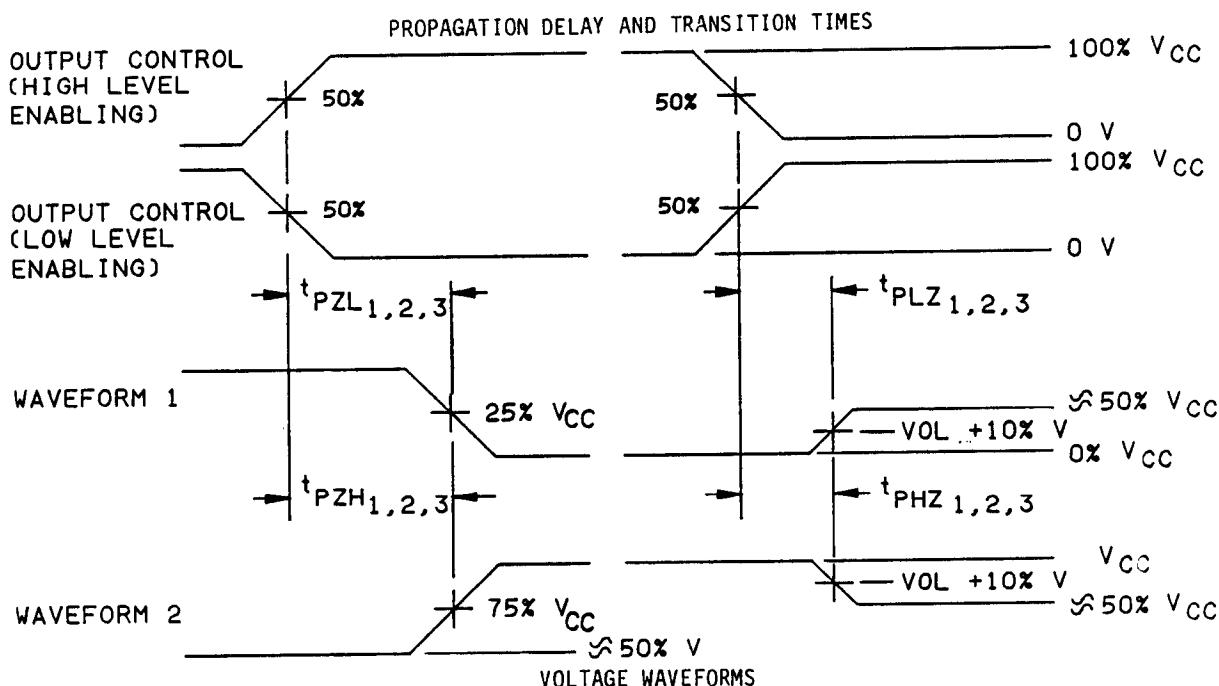
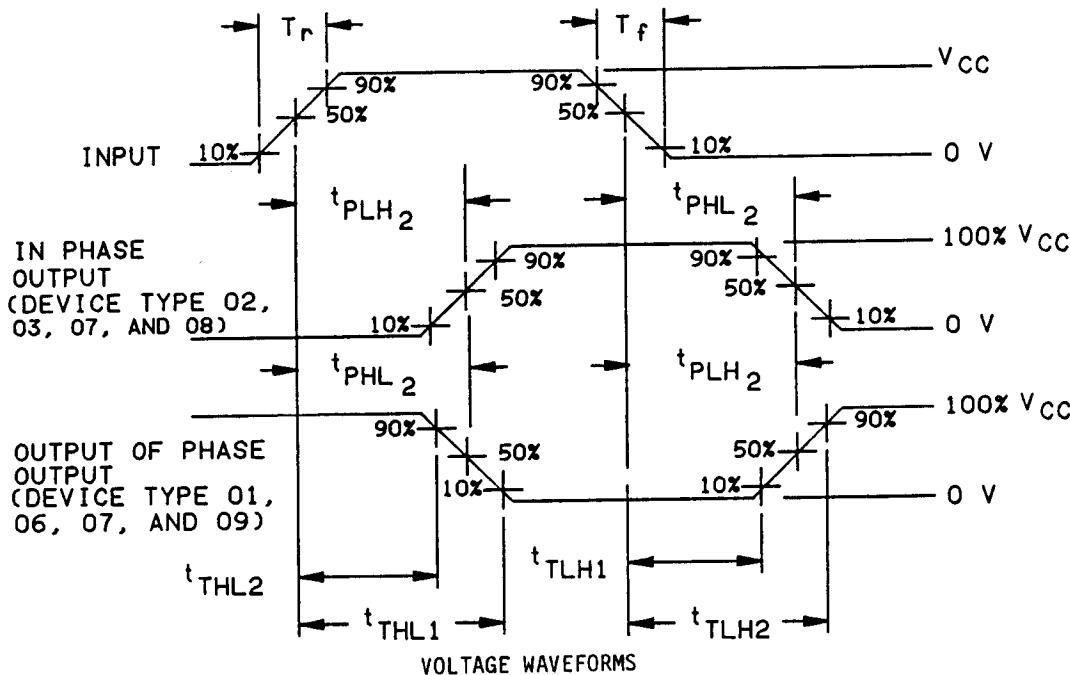
1. The input pulse shall have the following characteristics:
 $t_f = t_r \leq 6\mu s$, $V_{gen} = 4.5 V$
2. $R_L = 1 k\Omega \pm 5\%$.
3. $C_L = 50 pF \pm 10\%$, including scope probe, wiring, and stray capacitance without package in test fixture.
4. Voltage measurements are to be made with respect to network ground terminal.
5. Output connected to V_{CC} for t_{PLZ} and t_{PZL} ; and to GND for t_{PHZ} and t_{PZH} , see figure 4A.

FIGURE 4. Switching time test circuit and waveforms - Continued.

CLOCK TO OUTPUT (DEVICE TYPES 08 and 09)SELECT TO OUTPUTS (DEVICE TYPES 08 and 09)

NOTE: $t_{HOLD} \leq 5$ ns, $t_{setup} \leq 30$ ns, are $t_p(\text{clock}) \leq 30$ ns.

FIGURE 4. Switching time test circuit and waveforms - Continued.



ENABLE AND DISABLE TIMES, THREE-STATE OUTPUTS, ALL DEVICE TYPES

NOTES:

1. Input pulse shall have following characteristics: $t_r = t_f \leq 6$ ns; PRR ≤ 1 MHz; duty cycle = 50%
2. All unused inputs are tied to V_{CC}
3. $t_{THL1} - t_{THL2} = t_{THL}$; $t_{TLH2} - t_{TLH1} = t_{TLH}$

FIGURE 4. Switching time test circuit and waveforms - Continued.

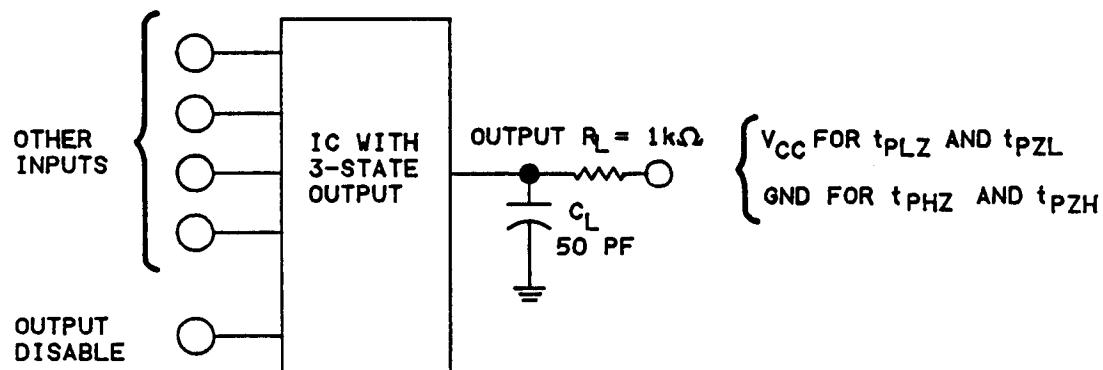
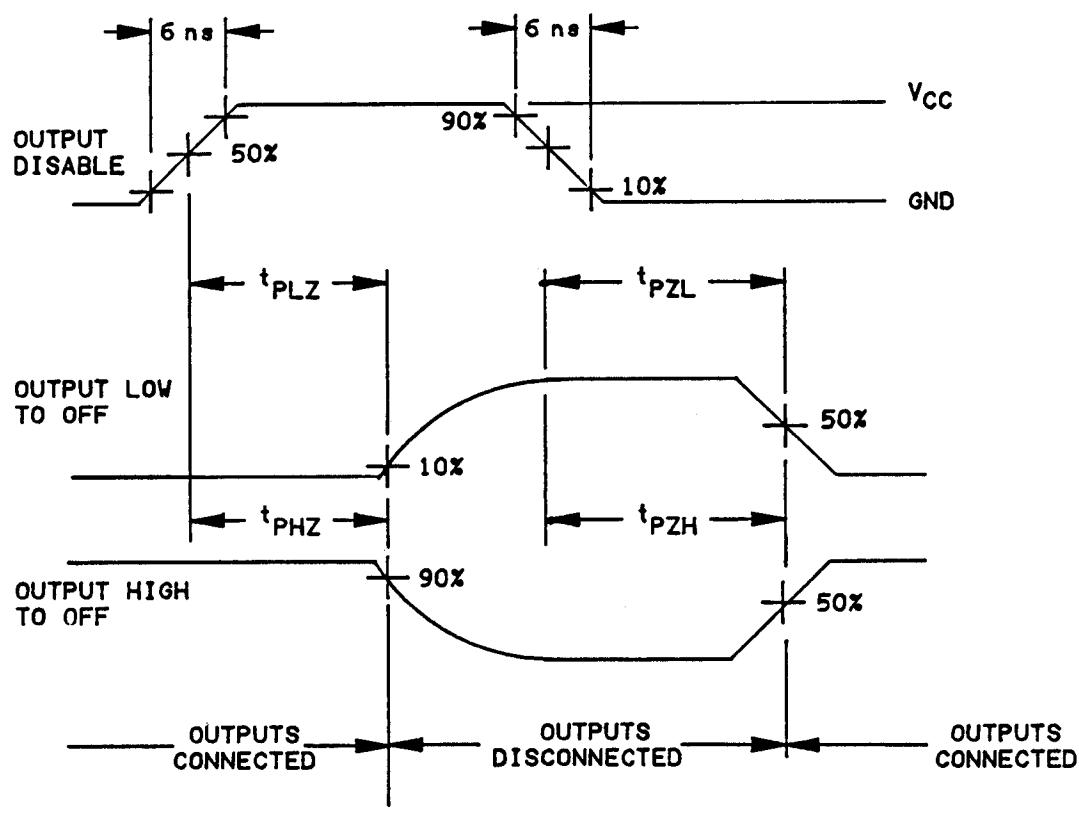
FIGURE 4A. Three-state propagation delay wave shapes and test circuit.

TABLE III. Group A inspection for device type 01.

Symbol	MIL-STD-883 method	Case 2 Case C	Test 1 Units												Test 1 Units												
			Terminal conditions $\frac{V}{I}$				Measured terminal conditions $\frac{V}{I}$				Subgroup 1				Subgroup 2				Subgroup 3				Unit				
Test no.	GT	NC	A1	A2	A3	A4	GND	B4	B3	B2	B1	NC	G2	VCC	GND	GT	GND	GT	GND	GT	GND	GT	GND	GT	GND	GT	GND
V_{IC} (pos)	1	1 mA																									
V_{IC} (neg)	2	-1 mA																									
I_{CC}	3	-1 mA																									
V_{IC} (pos)	4																										
I_{CC}	5	GND	6 V	6 V	6 V	6 V	GND	6 V	6 V	6 V	6 V	GND	6 V	6 V	GND	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	
I_{CC}	6	GND	6 V	6 V	6 V	6 V	GND	6 V	6 V	6 V	6 V	GND	6 V	6 V	GND	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	
I_{CC}	7	GND	6 V	6 V	6 V	6 V	GND	6 V	6 V	6 V	6 V	GND	6 V	6 V	GND	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	
I_{CC}	8	GND	6 V	6 V	6 V	6 V	GND	6 V	6 V	6 V	6 V	GND	6 V	6 V	GND	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	
V_{OH3}	9	6 V																									
V_{OH3}	10	4.2 V																									
V_{OH3}	11	*	*	*	*	*																					
V_{OH3}	12	*	*	*	*	*																					
V_{OH3}	13	*	*	*	*	*																					
V_{OH3}	14	1.2 V																									
V_{OH3}	15	*	*	*	*	*																					
V_{OH3}	16	*	*	*	*	*																					
V_{OH3}	17	*	*	*	*	*																					
V_{OH5}	18	4.2 V																									
V_{OH5}	19	*	*	*	*	*																					
V_{OH5}	20	*	*	*	*	*																					
V_{OH5}	21	*	*	*	*	*																					
V_{OH5}	22	1.2 V																									
V_{OH5}	23	*	*	*	*	*																					
V_{OH5}	24	*	*	*	*	*																					
V_{OH5}	25	*	*	*	*	*																					
V_{OL3}	26	4.2 V																									
V_{OL3}	27	*	*	*	*	*																					
V_{OL3}	28	*	*	*	*	*																					
V_{OL3}	29	1.2 V																									
V_{OL3}	30	*	*	*	*	*																					
V_{OL3}	31	*	*	*	*	*																					
V_{OL3}	32	*	*	*	*	*																					
V_{OL3}	33	*	*	*	*	*																					
V_{OL5}	34	4.2 V																									
V_{OL5}	35	*	*	*	*	*																					
V_{OL5}	36	*	*	*	*	*																					
V_{OL5}	37	*	*	*	*	*																					
V_{OL5}	38	1.2 V																									
V_{OL5}	39	*	*	*	*	*																					
V_{OL5}	40	*	*	*	*	*																					
V_{OL5}	41	*	*	*	*	*																					
I_{OL4}	42	4 V																									
I_{OL4}	43	*	*	*	*	*																					
I_{OL4}	44	*	*	*	*	*																					
I_{OL4}	45	*	*	*	*	*																					
I_{OL4}	46	GND																									
I_{OL4}	47	*	*	*	*	*																					
I_{OL4}	48	*	*	*	*	*																					
I_{OL4}	49	*	*	*	*	*																					

TABLE III. Group A inspection for device type 01 - Continued.

Symbol	MIL-STD-883 Case 2 method	Terminal conditions T_1												Test Units												Subgroup 1				Subgroup 2				Subgroup 3							
		Case 2				Case 3				Case 5				Case 7				Case 10				Case 13				Measured terminal				$T_C = +25^\circ\text{C}$				$T_C = +25^\circ\text{C}$				$T_C = -55^\circ\text{C}$			
		1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	11	12	13	14	15	16	17	18	19	20	mA									
I _{IN} /I _{OUT}	50	2/ μ	-	0 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	A1	A2	A3	A4	B1	B2	B3	B4	C1	C2	2.0									
	51	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-										
	52	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-									
	53	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-									
	54	1.12 V	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-									
	55	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-									
	56	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-									
	57	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-									
I _{IN} /I _{OUT}	58	2/ μ	-	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	A1	A2	A3	A4	B1	B2	B3	B4	C1	C2	-2.0									
	59	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-									
	60	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-									
	61	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-									
	62	1.12 V	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-									
	63	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-									
	64	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-									
	65	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-									
I _{IN}	3010	65	6 V	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-									
	67	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-									
I _{IL}	3009	69	6 V	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-									
	69	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-									

See footnotes at end of table.

TABLE III. Group A inspection for device type 01 - Continued.

Symbol	HLI-STD-883 method	Test no.	GT	NC	terminal conditions Σ										test limits										
					Subgroup 7					Subgroup 8					Subgroup 9					Measured terminal	TC = +25°C	TC = +125°C	TC = -55°C	TC = -40°C	
					Case 2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20		
Truth table tests 5/		80	B	A	A	A	B	B	L	H	H	A	A	B	B	Z	Z	Z	Z	Z	Z	Z	Z		
		81	B	A	B	B	L	L	H	H	H	A	A	B	B	Z	Z	Z	Z	Z	Z	Z	Z		
		82	A	A	A	A	A	A	A	A	A	A	A	B	B	Z	Z	Z	Z	Z	Z	Z	Z		
		83	A	A	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z		
		84	A	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z		
		85	B	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z	Z		
t _{THL}	3004 (Fig. 4)	.86	4.5 V			OUT	OUT			GND			IN	IN	IN	IN		4.5 V	4.5 V	A1	2	12	ns		
	87	"																		A2	"	"	"		
	88	"																	A3	"	"	"			
	89	GND					IN	IN											A4	"	"	"			
	90																		B1	"	"	"			
	91																		B2	"	"	"			
	92																		B3	"	"	"			
	93																		B4	"	"	"			
t _{TILH}	3004 (Fig. 4) to 101	94																	2	"	2	"			
t _{PHL2}	3003 (Fig. 4) to 102	102	GND			IN	IN			GND			IN	IN	IN	IN		4.5 V	4.5 V	A1 to B1	3	17	3	17	
	103	"																	A2 to B2	"	"	"			
	104	"																	A3 to B3	"	"	"			
	105	"																	A4 to B4	"	"	"			
	106	4.5 V					OUT	OUT											B1 to A1	"	"	"			
	107	"																	B2 to A2	"	"	"			
	108	"																	B3 to A3	"	"	"			
	109	"																	B4 to A4	"	"	"			
t _{PLH2}	3003 (Fig. 4) to 110	110																	3	"	3	"	3	"	
t _{PLH1}	3003 (Fig. 4) to 118	118	IN			GND				GND			OUT	OUT	OUT	OUT		4.5 V	4.5 V	G1 to B1	4	26	4	26	
	119	"																	G2 to B2	"	"	"			
	120	"																	G3 to B3	"	"	"			
	121	"																	G4 to B4	"	"	"			
	122	4.5 V					OUT	OUT											G1 to A1	"	"	"			
	123	"																	G2 to A2	"	"	"			
	124	"																	G3 to A3	"	"	"			
	125	"																	G4 to A4	"	"	"			
t _{PZL1}	3003 (Fig. 4) to 126	126	IN			4.5 V	4.5 V			GND			OUT	OUT	OUT	OUT		4.5 V	4.5 V	G1 to B1	4	35	4	35	
	127	"																	G2 to B2	"	"	"			
	128	"																	G3 to B3	"	"	"			
	129	4.5 V																	G4 to B4	"	"	"			
	130	"																	G1 to A1	"	"	"			
	131	"																	G2 to A2	"	"	"			
	132	"																	G3 to A3	"	"	"			
	133	"																	G4 to A4	"	"	"			

Same tests, terminal conditions, and limits as specified above for t_{THL}.

Same terminal conditions and terminals as specified above for t_{PHL2}.

TABLE III. Group A inspection for device type 01 - Continued.

Symbol	MIL-STD-883 Method	Case 2 (Case C)	Terminal conditions ^{1/}												Test limits						
			Subgroup 11				Subgroup 10				Subgroup 9				Measured		Subgroup 10		Subgroup 9		
			TC = -55°C	TC = -25°C	TC = 25°C	TC = 125°C	TC = -55°C	TC = -25°C	TC = 25°C	TC = 125°C	TC = -55°C	TC = -25°C	TC = 25°C	TC = 125°C	Min	Max	Min	Max	Min	Max	
tpHZ1	3.03 (F19. 4)	134	IN	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	14.5 V	GT to B1	4	30	4	30	ns	
<u>10/</u>	135	-	-	-	-	-	-	-	-	-	-	-	-	-	GT to B2	-	-	-	-	-	
	136	-	-	-	-	-	-	-	-	-	-	-	-	-	GT to B3	-	-	-	-	-	
	137	-	-	-	-	-	-	-	-	-	-	-	-	-	GT to B4	-	-	-	-	-	
	138	4.5 V	-	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	GT to A1	-	-	-	-	-	
	139	-	-	-	-	-	-	-	-	-	-	-	-	-	GT to B2	-	-	-	-	-	
	140	-	-	-	-	-	-	-	-	-	-	-	-	-	GT to A2	-	-	-	-	-	
	141	-	-	-	-	-	-	-	-	-	-	-	-	-	GT to B3	-	-	-	-	-	
	-	-	-	-	-	-	-	-	-	-	-	-	-	-	GT to B4	-	-	-	-	-	
	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
tpLZ1	3.03 (F19. 4)	142	IN	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	GT to B1	-	-	-	-	-
<u>9/</u>	143	-	-	-	-	-	-	-	-	-	-	-	-	-	GT to B2	-	-	-	-	-	
	144	-	-	-	-	-	-	-	-	-	-	-	-	-	GT to B3	-	-	-	-	-	
	145	-	-	-	-	-	-	-	-	-	-	-	-	-	GT to B4	-	-	-	-	-	
	146	4.5 V	-	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	4.5 V	GT to A1	-	-	-	-	-
	147	-	-	-	-	-	-	-	-	-	-	-	-	-	GT to B2	-	-	-	-	-	
<u>148</u>	148	-	-	-	-	-	-	-	-	-	-	-	-	-	GT to A2	-	-	-	-	-	
	149	-	-	-	-	-	-	-	-	-	-	-	-	-	GT to B3	-	-	-	-	-	

See footnotes at end of table.

TABLE III. Group A inspection for device type 02.

Symbol	MIL-STD-883 method	Terminal conditions \overline{V}														Test limits													
		Case 2				Case C				Subgroup 1 $T_C = +25^\circ\text{C}$				Subgroup 2 $T_C = +125^\circ\text{C}$				Subgroup 3 $T_C = -55^\circ\text{C}$				Unit							
		2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	Measured terminal	Subgroup 1 $T_C = +25^\circ\text{C}$	Subgroup 2 $T_C = +125^\circ\text{C}$	Subgroup 3 $T_C = -55^\circ\text{C}$	Unit				
Y _{IC} (pos)	1	NC	A1	A2	A3	A4	GND	B4	B3	B2	B1	NC	62	V _{CC}	GND	GND	GND	GND	GND	GND	GT	0.4	1.5	0.4	1.5				
Y _{IC} (neg)	2	1 mA													1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	GT	0.4	1.5	0.4	1.5				
I _{CC}	3	-1 mA																			GT	-1.5	-1.5	-1.5	-1.5				
I _{CCZ}	4																				GT	1/62	1/62	1/62	1/62				
Y _{OH3}	5	6 V																			GND	6 V	6 V	6 V	6 V				
Y _{OH3}	6	GND	6 V	6 V	6 V	6 V	GND	6 V	6 V	6 V	6 V	6 V	6 V	6 V	GND	6 V	6 V	6 V	6 V	6 V	GND	6 V	6 V	6 V	6 V				
I _{CC}	7	6 V																			GND	6 V	6 V	6 V	6 V				
I _{CCZ}	8																				GND	6 V	6 V	6 V	6 V				
Y _{OH3}	9	6 V																			GND	6 V	6 V	6 V	6 V				
Y _{OH3}	10	4.2 V																			4.2 V	1.2 V	1.2 V	1.2 V	1.2 V				
Y _{OH3}	11	-20 μ A																			GND	6 V	6 V	6 V	6 V				
Y _{OH3}	12	-20 μ A																			GND	6 V	6 V	6 V	6 V				
Y _{OH3}	13	-20 μ A																			GND	6 V	6 V	6 V	6 V				
Y _{OH3}	14	1.2 V																			GND	6 V	6 V	6 V	6 V				
Y _{OH3}	15	1.2 V																			GND	6 V	6 V	6 V	6 V				
Y _{OH3}	16	-20 μ A																			GND	6 V	6 V	6 V	6 V				
Y _{OH3}	17	-20 μ A																			GND	6 V	6 V	6 V	6 V				
Y _{OH5}	18	4.2 V																			4.2 V	1.2 V	1.2 V	1.2 V	1.2 V				
Y _{OH5}	19	-7.8 mA																			GND	6 V	6 V	6 V	6 V				
Y _{OH5}	20	-7.8 mA																			GND	6 V	6 V	6 V	6 V				
Y _{OH5}	21	1.2 V																			GND	6 V	6 V	6 V	6 V				
Y _{OH5}	22	1.2 V																			GND	6 V	6 V	6 V	6 V				
Y _{OH5}	23	-7.8 mA																			GND	6 V	6 V	6 V	6 V				
Y _{OH5}	24	-7.8 mA																			GND	6 V	6 V	6 V	6 V				
Y _{OH5}	25	-7.8 mA																			GND	6 V	6 V	6 V	6 V				
Y _{OL3}	26	4.2 V																			4.2 V	6 V	6 V	6 V	6 V				
Y _{OL3}	27	20 μ A																			GND	6 V	6 V	6 V	6 V				
Y _{OL3}	28	20 μ A																			GND	6 V	6 V	6 V	6 V				
Y _{OL3}	29	4.2 V																			GND	6 V	6 V	6 V	6 V				
Y _{OL3}	30	1.2 V																			GND	6 V	6 V	6 V	6 V				
Y _{OL3}	31	-7.8 mA																			GND	6 V	6 V	6 V	6 V				
Y _{OL3}	32	-7.8 mA																			GND	6 V	6 V	6 V	6 V				
Y _{OL3}	33	-7.8 mA																			GND	6 V	6 V	6 V	6 V				
Y _{OL5}	34	4.2 V																			4.2 V	4.2 V	4.2 V	4.2 V	4.2 V				
Y _{OL5}	35	7.8 mA																			GND	6 V	6 V	6 V	6 V				
Y _{OL5}	36	7.8 mA																			GND	6 V	6 V	6 V	6 V				
Y _{OL5}	37	1.2 V																			GND	6 V	6 V	6 V	6 V				
Y _{OL5}	38	4.2 V																			GND	6 V	6 V	6 V	6 V				
Y _{OL5}	39	4.2 V																			GND	6 V	6 V	6 V	6 V				
Y _{OL5}	40	-7.8 mA																			GND	6 V	6 V	6 V	6 V				
Y _{OL5}	41	-7.8 mA																			GND	6 V	6 V	6 V	6 V				
I _{OS4}	42	4 V																			4 V	4 V	4 V	4 V	4 V				
I _{OS4}	43	-10																			A1	-10	-10	-10	-10				
I _{OS4}	44	-10																			A2	-10	-10	-10	-10				
I _{OS4}	45	-10																			A3	-10	-10	-10	-10				
I _{OS4}	46	-10																			A4	-10	-10	-10	-10				
I _{OS4}	47	-10																			B1	-10	-10	-10	-10				
I _{OS4}	48	-10																			B2	-10	-10	-10	-10				
I _{OS4}	49	-10																			B3	-10	-10	-10	-10				
I _{OS4}	50	-10																			B4	-10	-10	-10	-10				

See footnotes at end of table.

TABLE III. Group A inspection for device type 02 - Continued.

Symbol	MIL-STD-883 Method	Case 2 Case C	Test conditions \underline{V}												Test limits						Unit
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19
Test no.	ET	NC	A1	A2	A3	A4	GND	B4	B3	B2	B1	NC	G2	I _{VCC}	Measured terminal	Subgroup 1 $T_C = +25^\circ\text{C}$	Subgroup 2 $T_C = +125^\circ\text{C}$	Subgroup 3 $T_C = -55^\circ\text{C}$	Unit		
I _{1H} / I _{OZH}	50 51 52 53 54 55 56 57	2/ -	6 V	6 V	6 V	6 V	GND	-	-	-	-	-	-	-	4.2 V	6 V	A1	A2	A3	A4	2.0 mA
I _{1L} / I _{OZL}	58 59 60 61 62 63 64 65	2/ -	1.2 V	2/ -	2/ -	2/ -	GND	-	-	-	-	-	-	-	4.2 V	-	A1	A2	A3	A4	-2.2 mA
I _{1H}	3010	66	6 V	-	-	-	GND	-	-	-	-	-	-	-	2/ -	2/ -	GND	-	-	-	-
I _{1L}	3009	68	GND	-	-	-	GND	-	-	-	-	-	-	-	GND	-	GT	GT	GT	GT	-1.2 mA
C _{1/0}	70 71 72 73 74 75 76 77	6 V	3/ -	3/ -	3/ -	3/ -	GND	-	-	-	-	-	-	-	GND	6 V	A1	A2	A3	A4	20 PF
C _C	78 79	3/ -	-	-	-	-	-	-	-	-	-	-	-	-	3/ -	3/ -	GND	GT	GT	GT	10 PF

See footnotes at end of table.

TABLE III. Group A inspection for device type 02 - Continued.

Symbol	MIL-SID-883 method	Case 2 (Case C)	Test limits												Measured terminal				
			Terminal conditions ΣU						Measured terminal						Subgroup 10 $T_C = +125^\circ C$	Subgroup 9 $T_C = +25^\circ C$	Subgroup 11 $T_C = -55^\circ C$	Unit	
Test no.	GT	NC	A1	A2	A3	A4	GND	B4	B3	B2	B1	NC	G2	VCC	Min	Max	Min	Max	
Truth table tests $\Sigma /$																			
t _{THL}	80 (Fig. 4)	B H	B H	A L	A L	A B	A GND	H -	A A	L B	L B	H B	H B	B 4.5 V	6/ -				
	81 82 83 84 85	A A A A B	B H L Z Z	B H L Z Z	B H L Z Z	B H B Z Z	B GND	H -	A A	B B	A B	H B	H B	B 4.5 V	6/ -				
t _{TLH}	3004 (Fig. 4)	86 87 88 89 90 91 92 93	4.5 V -	OUT IN IN IN GND -	OUT OUT OUT OUT -	OUT IN IN IN	IN -	IN OUT OUT OUT -	IN OUT OUT OUT -	IN OUT OUT OUT -	IN OUT OUT OUT -	IN OUT OUT OUT -	4.5 V -	4.5 V -	A1 A2 A3 A4 B1 B2 B3 B4	2 2 2 2 2 2 2 2	12 12 12 12 12 12 12 12	ns - - - - - - -	
t _{PLH2}	3003 (Fig. 4)	102 103 104 105 106 107 108 109	GND -	IN IN IN IN 4.5 V -	GND -	IN IN IN IN OUT OUT OUT OUT	GND -	OUT OUT OUT OUT IN IN IN IN	OUT OUT OUT OUT IN IN IN IN	OUT OUT OUT OUT IN IN IN IN	OUT OUT OUT OUT IN IN IN IN	OUT OUT OUT OUT IN IN IN IN	GND -	4.5 V -	A1 to B1 A2 to B2 A3 to B3 A4 to B4 B1 to A1 B2 to A2 B3 to A3 B4 to A4	4 4 4 4 4 4 4 4	17 17 17 17 17 17 17 17	4 4 4 4 4 4 4 4	17 17 17 17 17 17 17 17
t _{PLH2}	3003 (Fig. 4)	110 117	10 117	Same terminal conditions and measured terminals as specified above for t _{PLH2} .															
t _{PZH1}	3003 (Fig. 4)	118 119 120 121 122 123 124 125	IN -	4.5 V 4.5 V 4.5 V 4.5 V 4.5 V 4.5 V 4.5 V 4.5 V	GND -	4.5 V 4.5 V 4.5 V 4.5 V 4.5 V 4.5 V 4.5 V 4.5 V	GND -	OUT OUT OUT OUT OUT OUT OUT OUT	OUT OUT OUT OUT OUT OUT OUT OUT	OUT OUT OUT OUT OUT OUT OUT OUT	OUT OUT OUT OUT OUT OUT OUT OUT	OUT OUT OUT OUT OUT OUT OUT OUT	GND -	4.5 V -	E1 to B1 E1 to B2 E1 to B3 E1 to B4 G2 to A1 G2 to A2 G2 to A3 G2 to A4	4 4 4 4 4 4 4 4	4 4 4 4 4 4 4 4	4 4 4 4 4 4 4 4	
t _{PZH1}	3003 (Fig. 4)	126 127 128 129 130 131 132 133	IN -	GND -	GND -	GND -	GND -	OUT OUT OUT OUT OUT OUT OUT OUT	OUT OUT OUT OUT OUT OUT OUT OUT	OUT OUT OUT OUT OUT OUT OUT OUT	OUT OUT OUT OUT OUT OUT OUT OUT	GND -	GND -	E1 to B1 E1 to B2 E1 to B3 E1 to B4 G2 to A1 G2 to A2 G2 to A3 G2 to A4	27 27 27 27 27 27 27 27	1 1 1 1 1 1 1 1	36 36 36 36 36 36 36 36	27 27 27 27 27 27 27 27	

See footnotes at end of table.

TABLE III. Group A Inspection for device type 02 - Continued.

Symbol	MIL-STD-883 method	Terminal conditions <u>I_T</u>												Test limits						
		Case 2 Case C	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19
Test no.	GT	NC	A1	A2	A3	A4	GND	B4	B3	B2	B1	NC	V _{CC}	GND	4.5 V	GT to B1	4	32	4	32
<u>tPHZ1</u> <u>(Fig. 4)</u> <u>10/</u>	3003	134	IN	4.5 V	4.5 V	4.5 V	GND	*	*	OUT	OUT	*	*	GND	4.5 V	GT to B1	4	32	4	32
	135	*	*	*	*	*	*	*	*	OUT	OUT	*	*	*	*	GT to B2	*	*	*	*
	136	*	*	*	*	*	*	*	*	OUT	OUT	*	*	*	*	GT to B3	*	*	*	*
	137	*	*	*	*	*	*	*	*	OUT	OUT	*	*	*	*	GT to B4	*	*	*	*
	138	4.5 V	*	*	*	*	*	*	*	OUT	OUT	*	*	*	*	G2 to A1	*	*	*	*
	139	*	*	*	*	*	*	*	*	OUT	OUT	*	*	*	*	G2 to A2	*	*	*	*
	140	*	*	*	*	*	*	*	*	OUT	OUT	*	*	*	*	G2 to A3	*	*	*	*
	141	*	*	*	*	*	*	*	*	OUT	OUT	*	*	*	*	G2 to A4	*	*	*	*
	3003	142	IN	GND	GND	GND	*	*	*	OUT	OUT	*	*	GND	*	GT to B1	*	*	*	*
	143	*	*	*	*	*	*	*	*	OUT	OUT	*	*	*	*	GT to B2	*	*	*	*
<u>tPZ1</u> <u>9/</u>	144	*	*	*	*	*	*	*	*	OUT	OUT	*	*	*	*	GT to B3	*	*	*	*
	145	*	*	*	*	*	*	*	*	OUT	OUT	*	*	*	*	GT to B4	*	*	*	*
	146	4.5 V	*	*	*	*	*	*	*	OUT	OUT	*	*	*	*	G2 to A1	*	*	*	*
	147	*	*	*	*	*	*	*	*	OUT	OUT	*	*	*	*	G2 to A2	*	*	*	*
	148	*	*	*	*	*	*	*	*	OUT	OUT	*	*	*	*	G2 to A3	*	*	*	*
	149	*	*	*	*	*	*	*	*	OUT	OUT	*	*	*	*	G2 to A4	*	*	*	*

See footnotes at end of table.

TABLE III. Group A inspection for device type 03.

See footnotes at end of table.

TABLE III. Group A inspection for device type 03 - Continued.

See footnotes at end of table.

TABLE III. Group A inspection for device type D3 - Continued.

Symbol	MIL-STD-883 Cases 2, 3, 5	Test no.	Terminal conditions $\frac{V_{DD}}{V_{SS}}$												Test limits															
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	Measured terminal voltage V_C at $T_C = +25^\circ\text{C}$	Subgroup 1 $T_C = +125^\circ\text{C}$	Subgroup 2 $T_C = +55^\circ\text{C}$	Subgroup 3 $T_C = -55^\circ\text{C}$				
Method	R	DIR	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18	A19	A20	Min	Max	Min	Max	Min	Max		
V _{D5}	3007	90	1.2 V	7.8 mA	7.8 mA	7.8 mA	7.8 mA	7.8 mA	7.8 mA	7.8 mA	7.8 mA	0.26	0.4	0.26	0.4	0.26	0.4													
	91	
	92
	93
	94
	95
	96
	97	98	4.2 V	1.2 V	1.2 V	1.2 V	1.2 V	1.2 V	1.2 V	1.2 V	1.2 V	1.2 V	1.2 V	1.2 V	1.2 V	1.2 V	1.2 V	1.2 V	1.2 V	1.2 V	1.2 V	1.2 V	7.8 mA	7.8 mA	7.8 mA	7.8 mA	7.8 mA	7.8 mA		
	99	100
	101	102
	103	104
	105	106
	107	108
	109	110
	111	112
	113	114	4.2 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	
	115	116
	117	118
	119	120
	121	122
	123	124	1.2 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	
	125	126
	127	128
	129	130	4.2 V	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	
	131	132
	133	134
	135	136
	137	138

See footnotes at end of table.

TABLE III. Group A inspection for device type 03 - continued.

see footnotes at end of table.

TABLE III. Group A inspection for device type 03 - Continued.

See footnotes at end of table.

TABLE III. Group A Inspection for device type 0J - Continued.

Symbol	MIL-STD-883 Cases 2, 3, 4, 5, 6, 7, 8, 9, 10, 11, 12, 13, 14, 15, 16, 17, 18, 19, 20	Test 11										Test 111													
		Terminal conditions 11					Measured Subgroup 9					Subgroup 10					Subgroup 11								
		Test No.	DIR	A1	A2	A3	A4	A5	A6	A7	A8	GND	B8	B7	B6	B5	B4	B3	B2	B1	G	Min	Max	Min	Max
^{10/} ^{10/} ^{10/}	^{10/} 2003 (Fig. 4)	245	CMD	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	CMD	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	246	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	248	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	249	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	250	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	251	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	253	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	
	254	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	255	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	256	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
^{10/} ^{10/} ^{10/}	^{10/} 257	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	258	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	259	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	260	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	261	2003 (Fig. 4)	261	Same terminal conditions and measured terminals as specified above for t _{PL1} .										4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V
	262	216	Same terminal conditions and measured terminals as specified above for t _{PL1} .										4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V					
	263	277	WEH	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	CMD	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	264	278	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	265	279	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
^{9/} ^{9/} ^{9/}	^{9/} 280	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	281	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	282	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	283	284	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	285	285	6 V	CMD	CMD	CMD	CMD	CMD	CMD	CMD	CMD	CMD	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	286	286	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	287	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	288	288	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	289	289	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	290	290	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
^{9/}	^{9/} 291	291	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
	292	292	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	4.5 V	4.5 V	4.5 V	4.5 V	
^{9/}	^{9/} 293	293	Same terminal conditions and measured terminals as specified above for t _{PL1} .										4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V					
	308	308	See footnotes at end of table.										4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V					

TABLE III. Group A inspection for device type 06.

Symbol Method	MIL- Std-003 Cases 2, R	Test 1 (Units)												Test 2 (Units)												
		Terminal conditions 1/						Measured Subgroup 1/ terminal 1C = 25°C						Subgroup 2/ terminal 1C = +125°C												
Test No.	0IR	A1	A2	A3	A4	A5	A6	A7	A8	GND	88	87	86	85	84	83	82	81	80	Min	Max	Min	Max	Min	Max	
V _C (pos)	1	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	GND	-	-	-	-	-	-	-	-	-	0.4	1.5	-	-	-	-	
	2	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	3	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	4	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	5	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	6	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	7	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	8	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	9	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	10	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	11	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	12	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	13	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	14	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	15	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	16	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	17	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	18	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	19	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	20	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	21	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	22	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	23	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	24	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	25	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	26	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	27	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	28	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	29	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	30	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	31	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	32	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
I _{CC}	3005	33	6 V	6 V	6 V	6 V	6 V	6 V	6 V	GND	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V
	34	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	35	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	36	-	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
I _{CCZ}	3005	37	-	-	-	-	-	-	-	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-

See footnotes at end of table.

TABLE III. Group A Inspection for device type 06 - Continued.

Symbol	Mil- method	Symbol Cases 2, 14	Terminal conditions V_T												Test limits												
			Measured						Measured						Measured												
			Test No.	DIN	A1	A2	A3	A4	A5	A6	A7	A8	GND	B8	B7	B6	B5	B4	B3	B2	B1	E	VCC	Min	Max		
V_{DH3}	3006	38	1.2 V	-20 μ A	AI	5.95	5.95																				
	41	40																							A2	-	-
	42	41																							A3	-	-
	43	42																							A4	-	-
	44	43																							A5	-	-
	45	44																							A6	-	-
	46	45																							A7	-	-
	47	46																							A8	-	-
	48	47																							B1	-	-
	49	48																							B2	-	-
	50	49																							B3	-	-
	51	50																							B4	-	-
	52	51																							B5	-	-
	53	52																							B6	-	-
																									B7	-	-
																									B8	-	-
V_{DL5}	3006	54	Same tests and terminal conditions as for V_{DH3} except $I_{ON} = -7.8 \mu$ A.												5.48						5.48						
	60	69																									
V_{DL3}	3007	70	1.2 V	20 μ A	AI	.05	.05																				
	71	72																							A2	-	-
	73	74																							A3	-	-
	75	76																							A4	-	-
	77	78																							A5	-	-
	79	80																							A6	-	-
	81	82																							A7	-	-
	83	84																							B1	-	-
	85	86	Same tests and terminal conditions as for V_{DL3} except $I_{ON} = 7.8 \mu$ A.												0.26						0.4						
	101																										
V_{DL4}	3007	102	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND		
	103	104																							A1	-1.3	-1.35
	105	106																							A2	-	-1.0
	107	108																							A3	-	-1.35
	109	110																							A4	-	-
	111	112																							A5	-	-
	113	114																							A6	-	-
	115	116																							B1	-	-
	117																								B2	-	-

See footnotes at end of table.

TABLE III. Group A inspection for device type 06 - Continued.

See footnotes at end of table.

TABLE III. Group A inspection for device type 06 - Continued.

See footnotes at end of table.

TABLE III. Group A inspection for device type 06 - Continued.

Symbol	NLL-SID-883 Cases 2: R	terminal conditions 1/												Test limits						
		1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19
Test no.	D1R	A1	A2	A3	A4	A5	A6	A7	A8	GND	B6	B7	B8	B5	B4	B3	B2	B1	T	V _{CC}
t _{pH22}	240 (Fig. 4)	241	GND	0.01T	0.01T	0.01T	0.01T	0.01T	0.01	0.01										
10/	242	243	244	245	246	247	248	249	250	251	252	253	254	255	256	257	258	259	260	261
t _{pH22}	260 (Fig. 4)	261	GND	0.01T	0.01T	0.01T	0.01T	0.01T	0.01	0.01										
10/	262	263	264	265	266	267	268	269	270	271	272	273	274	275	276	277	278	279	280	281
t _{pH22}	279 (Fig. 4)	280	281	282	283	284	285	286	287	288	289	290	291	292	293	294	295	296	297	298
10/	299	300	301	302	303	304	305	306	307	308	309	310	311	312	313	314	315	316	317	318
t _{pH22}	319 (Fig. 4)	320	321	322	323	324	325	326	327	328	329	330	331	332	333	334	335	336	337	338
10/	339	340	341	342	343	344	345	346	347	348	349	350	351	352	353	354	355	356	357	358
t _{pH22}	359 (Fig. 4)	360	361	362	363	364	365	366	367	368	369	370	371	372	373	374	375	376	377	378
10/	379	380	381	382	383	384	385	386	387	388	389	390	391	392	393	394	395	396	397	398
t _{pH22}	399 (Fig. 4)	400	401	402	403	404	405	406	407	408	409	410	411	412	413	414	415	416	417	418
10/	419	420	421	422	423	424	425	426	427	428	429	430	431	432	433	434	435	436	437	438
t _{pH22}	439 (Fig. 4)	440	441	442	443	444	445	446	447	448	449	450	451	452	453	454	455	456	457	458
10/	459	460	461	462	463	464	465	466	467	468	469	470	471	472	473	474	475	476	477	478
t _{pH22}	479 (Fig. 4)	480	481	482	483	484	485	486	487	488	489	490	491	492	493	494	495	496	497	498
10/	499	500	501	502	503	504	505	506	507	508	509	510	511	512	513	514	515	516	517	518
t _{pH22}	519 (Fig. 4)	520	521	522	523	524	525	526	527	528	529	530	531	532	533	534	535	536	537	538
10/	539	540	541	542	543	544	545	546	547	548	549	550	551	552	553	554	555	556	557	558
t _{pH22}	559 (Fig. 4)	560	561	562	563	564	565	566	567	568	569	570	571	572	573	574	575	576	577	578
10/	579	580	581	582	583	584	585	586	587	588	589	590	591	592	593	594	595	596	597	598
t _{pH22}	599 (Fig. 4)	600	601	602	603	604	605	606	607	608	609	610	611	612	613	614	615	616	617	618
10/	619	620	621	622	623	624	625	626	627	628	629	630	631	632	633	634	635	636	637	638
t _{pH22}	639 (Fig. 4)	640	641	642	643	644	645	646	647	648	649	650	651	652	653	654	655	656	657	658
10/	659	660	661	662	663	664	665	666	667	668	669	670	671	672	673	674	675	676	677	678
t _{pH22}	679 (Fig. 4)	680	681	682	683	684	685	686	687	688	689	690	691	692	693	694	695	696	697	698
10/	699	700	701	702	703	704	705	706	707	708	709	710	711	712	713	714	715	716	717	718
t _{pH22}	719 (Fig. 4)	720	721	722	723	724	725	726	727	728	729	730	731	732	733	734	735	736	737	738
10/	739	740	741	742	743	744	745	746	747	748	749	750	751	752	753	754	755	756	757	758
t _{pH22}	759 (Fig. 4)	760	761	762	763	764	765	766	767	768	769	770	771	772	773	774	775	776	777	778
10/	779	780	781	782	783	784	785	786	787	788	789	790	791	792	793	794	795	796	797	798
t _{pH22}	799 (Fig. 4)	800	801	802	803	804	805	806	807	808	809	810	811	812	813	814	815	816	817	818
10/	819	820	821	822	823	824	825	826	827	828	829	830	831	832	833	834	835	836	837	838
t _{pH22}	839 (Fig. 4)	840	841	842	843	844	845	846	847	848	849	850	851	852	853	854	855	856	857	858
10/	859	860	861	862	863	864	865	866	867	868	869	870	871	872	873	874	875	876	877	878
t _{pH22}	879 (Fig. 4)	880	881	882	883	884	885	886	887	888	889	890	891	892	893	894	895	896	897	898
10/	899	900	901	902	903	904	905	906	907	908	909	910	911	912	913	914	915	916	917	918
t _{pH22}	919 (Fig. 4)	920	921	922	923	924	925	926	927	928	929	930	931	932	933	934	935	936	937	938
10/	939	940	941	942	943	944	945	946	947	948	949	950	951	952	953	954	955	956	957	958
t _{pH22}	959 (Fig. 4)	960	961	962	963	964	965	966	967	968	969	970	971	972	973	974	975	976	977	978
10/	979	980	981	982	983	984	985	986	987	988	989	990	991	992	993	994	995	996	997	998
t _{pH22}	999 (Fig. 4)	1000	1001	1002	1003	1004	1005	1006	1007	1008	1009	1010	1011	1012	1013	1014	1015	1016	1017	1018

See footnotes at end of table.

Same tests and terminal conditions as specified above t_{pH22}.

TABLE III. Group A Inspection for device type D.

Symbol	MIL-STD-883 Cases 2: Method R	Terminal conditions V_T																			Test limits				Tilt			
		1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	Measured terminal voltage V_T	Subgroup 1 $T_C = +25^\circ C$	Subgroup 2 $T_C = +125^\circ C$	Subgroup 3 $T_C = -55^\circ C$				
Test No.	DIN	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18	A19	Min	Max	Min	Max	Min	Max		
I_{IC} (pos)	1	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	GND	A1	0.4 V / 1.5	-	-	-	-	Y
	2	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A2	-	-	-	-	-		
	4	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A3	-	-	-	-	-		
	5	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A4	-	-	-	-	-		
	6	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A5	-	-	-	-	-		
	7	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A6	-	-	-	-	-		
	8	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A7	-	-	-	-	-		
	9	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A8	-	-	-	-	-		
	10	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A9	-	-	-	-	-		
	11	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A10	-	-	-	-	-		
	12	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A11	-	-	-	-	-		
	13	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A12	-	-	-	-	-		
	14	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A13	-	-	-	-	-		
	15	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A14	-	-	-	-	-		
	16	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A15	-	-	-	-	-		
I_{IC} (neg)	17	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	GND	A1	-1.5	-	-	-	-	Y
	18	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A2	-	-	-	-	-		
	19	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A3	-	-	-	-	-		
	20	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A4	-	-	-	-	-		
	21	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A5	-	-	-	-	-		
	22	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A6	-	-	-	-	-		
	23	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A7	-	-	-	-	-		
	24	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A8	-	-	-	-	-		
	25	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A9	-	-	-	-	-		
	26	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A10	-	-	-	-	-		
	27	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A11	-	-	-	-	-		
	28	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A12	-	-	-	-	-		
	29	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A13	-	-	-	-	-		
	30	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A14	-	-	-	-	-		
	31	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A15	-	-	-	-	-		
	32	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A16	-	-	-	-	-		
I_{CC}	3005	33	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	GND	6 V	6 V	6 V	6 V	6 V	Y	
	34	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A17	-	-	-	-	-		
	35	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A18	-	-	-	-	-		
	36	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A19	-	-	-	-	-		
	37	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A20	-	-	-	-	-		
I_{CC2}	3005	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	A21	-	-	-	-	-		

See footnotes at end of table.

TABLE III. Group A inspection for device type 07 - Continued.

Symbol	MIL-STD-883 Cases 2, method R	Terminal conditions \underline{I}_T												Test limits															
		Measured Subgroup 1				Measured Subgroup 2				Measured Subgroup 3				Measured Subgroup 4				Measured Subgroup 5				Measured Subgroup 6							
		$T_C = +25^\circ C$		$T_C = +125^\circ C$		$T_C = -55^\circ C$		$T_C = -55^\circ C$		$T_C = +25^\circ C$		$T_C = +125^\circ C$		$T_C = -55^\circ C$		$T_C = +25^\circ C$		$T_C = +125^\circ C$		$T_C = -55^\circ C$		$T_C = +25^\circ C$		$T_C = +125^\circ C$		$T_C = -55^\circ C$			
Test no.	Test no.	V_{DD}	I_D	V_{DD}	I_D	V_{DD}	I_D	V_{DD}	I_D	V_{DD}	I_D	V_{DD}	I_D	V_{DD}	I_D	V_{DD}	I_D	V_{DD}	I_D	V_{DD}	I_D	V_{DD}	I_D	V_{DD}	I_D	V_{DD}	I_D		
Vol.3	3006	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26		
Vol.3	3007	39	40	41	42	43	44	45	46	47	48	49	50	51	52	53	54	55	56	57	58	59	60	61	62	63	64	65	
Vol.5	3006	54	Same tests and terminal conditions as for Vol.3 except $I_{OH} = -7.0 \mu A$.												5.48	5.2	5.48	-	-	-	-	-	-	-	-	-	-	-	
Vol.3	3007	71	72	73	74	75	76	77	78	79	80	81	82	83	84	85	86	87	88	89	90	91	92	93	94	95	96		
Vol.5	3007	70	71	72	73	74	75	76	77	78	79	80	81	82	83	84	85	86	87	88	89	90	91	92	93	94	95		
Vol.5	3007	96	Same tests and terminal conditions as for Vol.3 except $I_{OH} = 7.8 \mu A$.												-26	0.4	-26	-	-	-	-	-	-	-	-	-	-	-	
Vol.5	3011	102	103	104	105	106	107	108	109	110	111	112	113	114	115	116	117	118	119	120	121	122	123	124	125	126	127		
Vol.5	3011	101	Same tests and terminal conditions as for Vol.3 except $I_{OH} = 7.8 \mu A$.												1.4	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V	4 V
Vol.5	3011	103	104	105	106	107	108	109	110	111	112	113	114	115	116	117	118	119	120	121	122	123	124	125	126	127	128		

see footnotes at end of table.

TABLE III. Group A Inspection for device type 07 - Continued.

Symbol	MIL-STD-883 Cases 2, R	Test limits												Subgroup J, T = 25°C	Subgroup Z, T = 125°C	Measured terminal, T = 25°C	Measured terminal, T = 125°C	Test limit			
		1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20
Method	Test no.	AI	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18	A19	A20
I _{14H} / I _{14Z}	3010	118	1.4 V	0 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	2 V	2 V	2 V	2 V	2 V
	119	120	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	122	123	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	124	125	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	126	127	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	128	129	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	130	131	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	132	133	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
I _{14H}	3011	134	6 V	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	135	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
I _{14L} / I _{14ZL}	3010	136	1.2 V	GND	GND	GND	2 V	2 V	2 V	2 V	2 V										
	137	138	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	139	140	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	141	142	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	143	144	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	145	146	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	147	148	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	149	150	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	151	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
I _{14L}	3011	152	GND	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	153	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
C _{1/0}	154	155	0 V	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	156	157	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	158	159	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	160	161	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	162	163	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	164	165	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	166	167	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	168	169	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
C _L	170	171	0 V	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-

See footnote(s) at end of table.

TABLE III. Group A inspection for device type 07 - Continued.

see footnotes at end of table.

TABLE III. Group A inspection for device type 07 - Continued.

Symbol	MLI- method R	Cases 2, [Fig. 4] 10/ 10/	Terminal conditions $\frac{V}{I}$												Test results																	
			Test no.	DIR	A1	A2	A3	A4	A5	A6	A7	A8	IND	B8	B7	B6	B5	B4	B3	B2	B1	\bar{I}	V _{CC}	Measured subgroup 3 terminal; -55°C $+25^{\circ}\text{C}$ $+125^{\circ}\text{C}$ $+175^{\circ}\text{C}$	Subgroup 0 terminal; -55°C $+25^{\circ}\text{C}$ $+125^{\circ}\text{C}$ $+175^{\circ}\text{C}$	Test						
t _{p12}	3003	240	GND	OUT	IND	IND	IND	IND	IND	IND	IND	IND	IND	IND	IND	IND	4.5 V	4.5 V	4.5 V													
		241	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-						
		242	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-						
		243	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-						
		244	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-						
		245	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-						
		246	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-						
		247	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-						
		248	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-						
		249	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-						
		250	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-						
		251	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-						
		252	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-						
		253	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-						
		254	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-						
		255	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-						
		256	Same tests and terminal conditions as specified above t _{p12} .												-												9	44	9	39	9	14
t _{p12}	3003	[Fig. 4] 10/ 271	-												-												9	44	9	39	9	14
		272	GND	OUT	IND	IND	IND	IND	IND	IND	IND	IND	IND	IND	IND	IND	IND	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V									
		273	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		274	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		275	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		276	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		277	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		278	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		279	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		280	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		281	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		282	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		283	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		284	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		285	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		286	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		287	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
t _{p12}	3003	[Fig. 4] 288	Same tests and terminal conditions as specified above t _{p12} .												-												9	44	9	39	9	14
		289	See footnotes at end of table.												-												9	44	9	39	9	14

TABLE III. Group A Inspection for device type Da.

Symbol	MIL-STD-883 test method	Termination condition $\frac{V}{I}$																			Test Units									
		Case 3	2	3	4	5	6	7	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26	27	28		
Test No.	CAB	SAB	DIR	A1	A2	A3	A4	A5	A6	A7	A8	WHD	WHD	WHD	WHD	WHD	WHD	WHD	WHD	WHD	WHD									
(VIC) (pos)	1	1 mA																												
	2		1 mA																											
	3			1 mA																										
	4				1 mA																									
	5					1 mA																								
	6						1 mA																							
	7							1 mA																						
	8								1 mA																					
	9									1 mA																				
	10										1 mA																			
	11											1 mA																		
	12												1 mA																	
	13													1 mA																
	14														1 mA															
	15															1 mA														
	16																1 mA													
	17																	1 mA												
	18																		1 mA											
	19																			1 mA										
	20																				1 mA									
	21																					1 mA								
	22																						1 mA							
(VIC) (pos)	23		-1 mA																											
	24			-1 mA																										
	25				-1 mA																									
	26					-1 mA																								
	27						-1 mA																							
	28							-1 mA																						
	29								-1 mA																					
	30									-1 mA																				
	31										-1 mA																			
	32											-1 mA																		
	33												-1 mA																	
	34													-1 mA																
	35														-1 mA															
	36															-1 mA														
	37																-1 mA													
	38																	-1 mA												
	39																		-1 mA											
	40																			-1 mA										
	41																				-1 mA									
	42																					-1 mA								
	43																						-1 mA							

See footnotes at end of table.

TABLE III. Group A Inspection for device type OM - Continued.

Symbol	NIL-S10-Multicell 3 selected Case L	Test No.	CAB	Measured Termination Test Times															Unit	
				Termination Subgroup 1				Termination Subgroup 2				Termination Subgroup 3				Termination Subgroup 4				
				TC = -25°C	TC = +25°C	TC = +125°C	TC = +55°C	TC = -25°C	TC = +25°C	TC = +125°C	TC = +55°C	TC = -25°C	TC = +25°C	TC = +125°C	TC = +55°C	TC = -25°C	TC = +25°C	TC = +125°C	TC = +55°C	
I _{CC}	45	60	CAB	6V	6V	CAB	6V	6V	6V	6V	6V	CAB	6V	6V	CAB	6V	6V	6V	6V	s
I _{CC}	46	-	CAB	6V	6V	CAB	6V	6V	6V	6V	6V	CAB	6V	6V	CAB	6V	6V	6V	6V	s
I _{CC}	47	-	CAB	6V	6V	CAB	6V	6V	6V	6V	6V	CAB	6V	6V	CAB	6V	6V	6V	6V	s
I _{CC}	48	-	CAB	6V	6V	CAB	6V	6V	6V	6V	6V	CAB	6V	6V	CAB	6V	6V	6V	6V	s
I _{CC}	50	52	CAB	CAB	CAB	CAB	CAB	CAB	CAB	CAB	CAB	CAB	CAB	CAB	CAB	CAB	CAB	CAB	CAB	s
I _{OM3}	3005	51	1.2 V	1.2 V	1.2 V	-20 μ A	-20 μ A	-20 μ A	-20 μ A	-20 μ A	-20 μ A	-20 μ A	-20 μ A	-20 μ A	-20 μ A	-20 μ A	-20 μ A	-20 μ A	s	
I _{OM3}	52	53	54	55	56	57	58	59	60	61	62	63	64	65	66	67	68	69	70	s
I _{OM5}	3006	67	68	69	70	71	72	73	74	75	76	77	78	79	80	81	82	83	84	s
I _{OM5}	85	86	87	88	89	90	91	92	93	94	95	96	97	98	99	100	101	102	103	s
I _{OM3}	3007	63	64	65	66	67	68	69	70	71	72	73	74	75	76	77	78	79	80	s
I _{OM3}	83	84	85	86	87	88	89	90	91	92	93	94	95	96	97	98	99	100	101	s

See footnotes at end of table.

TABLE III. Group A inspection for device type 08 - Continued.

the features at end of table.

TABLE III. Gr cap A Inspection for device type 06 - Continued.

Symbol	MIL-R-3881J Test 3 method	Test Results												Measured Subgroup 1 Min Max	Measured Subgroup 2 Min Max	Measured Subgroup 3 Min Max													
		1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26	27	28
Case C	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26	27	28	29
Test no. CAB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB	5AB
111	147	148	149	149	150	150	151	152	152	153	153	154	155	155	156	156	157	157	158	158	159	159	160	160	161	161	162	162	
111H	2010	163	6 V	6 V	6 V	6 V	165	167	167	168	168	169	170	170	171	171	172	172	173	173	174	174	175	175	176	176	177	177	
111L	3069	169	6 V	6 V	6 V	6 V	170	171	172	172	173	173	174	174	175	175	176	176	177	177	178	178	179	179	180	180	181	181	
111R	175	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V	6 V
112	191	192	193	194	195	196	197	198	199	200	201	202	203	204	205	206	207	208	209	210	211	212	213	214	215	216	217	218	219

See footnotes at end of table.

TABLE III. Group A Inspection for device type 06 - Continued.

Symbol	MIL-M-3 method	Test 3	Terminal conditions β												Test limits													
			2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26	
Test 1	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26	27	
Test no. C48	548	31R	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18	A19	A20	A21	A22	A23	A24	A25	
Initial table series	3014	129	130	131	132	133	134	135	136	137	138	139	140	141	142	143	144	145	146	147	148	149	150	151	152	153	154	
Σ		260	261	262	263	264	265	266	267	268	269	270	271	272	273	274	275	276	277	278	279	280	281	282	283	284	285	
Final table series	3003	210	211	212	213	214	215	216	217	218	219	220	221	222	223	224	225	226	227	228	229	230	231	232	233	234	235	
Σ		226	227	228	229	230	231	232	233	234	235	236	237	238	239	240	241	242	243	244	245	246	247	248	249	250	251	252
Final table series	3004 (Fig. 4)	226	227	228	229	230	231	232	233	234	235	236	237	238	239	240	241	242	243	244	245	246	247	248	249	250	251	252
Σ		252	253	254	255	256	257	258	259	260	261	262	263	264	265	266	267	268	269	270	271	272	273	274	275	276	277	278

See footnotes at end of table.

See footnotes at end of table.

Same tests, terminal conditions, and limits as specified above for Fig.

See footnotes at end of table.

TABLE III. Group A inspection for device type 08 - Continued.

See footnotes at end of table.

TABLE III. Group A inspection for device type 08 - Continued.

See footnotes at end of table.

TABLE III. Group A inspection for device type 08 - Continued.

See footnotes at end of table.

TABLE III. Gr. 000-A Inspection for device type 09.

Symbol	ATEL STD-003 method	Case 3	Case 1	Case 1	Test Results												Test Yield															
					1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24				
Test No.	CAB	SAB	SAB	SAB	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18	A19	A20	A21	A22	A23	A24	Yield			
V _C (mV)	2	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA			
T _C (deg)	23	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	-1 mA	Yield			
	24	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1			
	25	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1		
	26	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	
	27	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1
	28	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1
	29	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1
	30	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1
	31	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1
	32	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1
	33	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1
	34	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1
	35	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1
	36	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1
	37	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1
	38	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1
	39	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1
	40	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1
	41	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1
	42	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1
	43	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1
	44	0.4	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1	1/1

See footnotes at end of table.

TABLE III. Group A Inspection for device type 09 - Continued.

Symbol	MIL-S10-881	Test J	Test Results												Unit													
			Subgroup J			Subgroup 2			Subgroup 1			Termination			Termination			Termination			Termination			Termination				
Method	Base 1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26	27	28
Test no.	CA8	SAB	0IR	AI	A2	A3	A4	A5	A6	A7	A8	GA0	GA1	GA2	GA3	GA4	GA5	GA6	GA7	GA8	GA9	GA10	GA11	GA12	GA13	GA14	GA15	GA16
I _{CC}	30.05	45	60	64	67	69	70	71	72	73	74	75	76	77	78	79	80	81	82	83	84	85	86	87	88	89	90	91
I _{CE2}	30.05	45	50	50	50	50	50	50	50	50	50	50	50	50	50	50	50	50	50	50	50	50	50	50	50	50	50	50
V _{BE3}	30.06	51	52	52	52	52	52	52	52	52	52	52	52	52	52	52	52	52	52	52	52	52	52	52	52	52	52	52
V _{BE5}	30.06	67	69	70	72	74	75	76	77	78	79	79	79	79	79	79	79	79	79	79	79	79	79	79	79	79	79	79
V _{BE6}	30.06	67	69	70	72	74	75	76	77	78	79	79	79	79	79	79	79	79	79	79	79	79	79	79	79	79	79	79
V _{BE7}	30.07	63	64	65	66	67	68	69	70	71	72	73	74	75	76	77	78	79	80	81	82	83	84	85	86	87	88	89

See footnotes at end of table.

TABLE III. Gr. comp A Inspection for device type 09 - Contined.

Symbol	MIL-S10-863 Test 3 method	Terminal connections "U"												Total Test													
		Test 1				Test 2				Test 3				Test 4				Test 5				Test 6					
		1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26
Test no.	CAB	101	102	103	104	105	106	107	108	109	110	111	112	113	114	115	116	117	118	119	120	121	122	123	124	125	126
VOL 5	3007	90	101	102	103	104	105	106	107	108	109	110	111	112	113	114	115	116	117	118	119	120	121	122	123	124	125
1054	3011	115	116	117	118	119	120	121	122	123	124	125	126	127	128	129	130	131	132	133	134	135	136	137	138	139	140
1054	3012	131	132	133	134	135	136	137	138	139	140	141	142	143	144	145	146	147	148	149	150	151	152	153	154	155	156

See footnotes at end of table.

TABLE III. Group A inspection for device type 03 - Continued.

see comment at end of table.

TABLE III. Group A inspection for service type 09 - Continued.

See footnotes at end of table.

TABLE III. Group A Inspection for device type 09 - Continued.

Symbol	MIL-STD-883C Test Method	Initial conditions										Test results																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																											
Test 09					Test 10					Test 11					Test 12																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																								
Test no.	CAB	SAB	DIR	A1	A2	A3	A4	A5	A6	A7	A8	DIR	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18	A19	A20	A21	A22	A23	A24	A25	A26	A27	A28	A29	A30	A31	A32	A33	A34	A35	A36	A37	A38	A39	A40	A41	A42	A43	A44	A45	A46	A47	A48	A49	A50	A51	A52	A53	A54	A55	A56	A57	A58	A59	A60	A61	A62	A63	A64	A65	A66	A67	A68	A69	A70	A71	A72	A73	A74	A75	A76	A77	A78	A79	A80	A81	A82	A83	A84	A85	A86	A87	A88	A89	A90	A91	A92	A93	A94	A95	A96	A97	A98	A99	A100	A101	A102	A103	A104	A105	A106	A107	A108	A109	A110	A111	A112	A113	A114	A115	A116	A117	A118	A119	A120	A121	A122	A123	A124	A125	A126	A127	A128	A129	A130	A131	A132	A133	A134	A135	A136	A137	A138	A139	A140	A141	A142	A143	A144	A145	A146	A147	A148	A149	A150	A151	A152	A153	A154	A155	A156	A157	A158	A159	A160	A161	A162	A163	A164	A165	A166	A167	A168	A169	A170	A171	A172	A173	A174	A175	A176	A177	A178	A179	A180	A181	A182	A183	A184	A185	A186	A187	A188	A189	A190	A191	A192	A193	A194	A195	A196	A197	A198	A199	A200	A201	A202	A203	A204	A205	A206	A207	A208	A209	A210	A211	A212	A213	A214	A215	A216	A217	A218	A219	A220	A221	A222	A223	A224	A225	A226	A227	A228	A229	A230	A231	A232	A233	A234	A235	A236	A237	A238	A239	A240	A241	A242	A243	A244	A245	A246	A247	A248	A249	A250	A251	A252	A253	A254	A255	A256	A257	A258	A259	A260	A261	A262	A263	A264	A265	A266	A267	A268	A269	A270	A271	A272	A273	A274	A275	A276	A277	A278	A279	A280	A281	A282	A283	A284	A285	A286	A287	A288	A289	A290	A291	A292	A293	A294	A295	A296	A297	A298	A299	A300	A301	A302	A303	A304	A305	A306	A307	A308	A309	A310	A311	A312	A313	A314	A315	A316	A317	A318	A319	A320	A321	A322	A323	A324	A325	A326	A327	A328	A329	A330	A331	A332	A333	A334	A335	A336	A337	A338	A339	A340	A341	A342	A343	A344	A345	A346	A347	A348	A349	A350	A351	A352	A353	A354	A355	A356	A357	A358	A359	A360	A361	A362	A363	A364	A365	A366	A367	A368	A369	A370	A371	A372	A373	A374	A375	A376	A377	A378	A379	A380	A381	A382	A383	A384	A385	A386	A387	A388	A389	A390	A391	A392	A393	A394	A395	A396	A397	A398	A399	A400	A401	A402	A403	A404	A405	A406	A407	A408	A409	A410	A411	A412	A413	A414	A415	A416	A417	A418	A419	A420	A421	A422	A423	A424	A425	A426	A427	A428	A429	A430	A431	A432	A433	A434	A435	A436	A437	A438	A439	A440	A441	A442	A443	A444	A445	A446	A447	A448	A449	A450	A451	A452	A453	A454	A455	A456	A457	A458	A459	A460	A461	A462	A463	A464	A465	A466	A467	A468	A469	A470	A471	A472	A473	A474	A475	A476	A477	A478	A479	A480	A481	A482	A483	A484	A485	A486	A487	A488	A489	A490	A491	A492	A493	A494	A495	A496	A497	A498	A499	A500	A501	A502	A503	A504	A505	A506	A507	A508	A509	A510	A511	A512	A513	A514	A515	A516	A517	A518	A519	A520	A521	A522	A523	A524	A525	A526	A527	A528	A529	A530	A531	A532	A533	A534	A535	A536	A537	A538	A539	A540	A541	A542	A543	A544	A545	A546	A547	A548	A549	A550	A551	A552	A553	A554	A555	A556	A557	A558	A559	A560	A561	A562	A563	A564	A565	A566	A567	A568	A569	A570	A571	A572	A573	A574	A575	A576	A577	A578	A579	A580	A581	A582	A583	A584	A585	A586	A587	A588	A589	A590	A591	A592	A593	A594	A595	A596	A597	A598	A599	A600	A601	A602	A603	A604	A605	A606	A607	A608	A609	A610	A611	A612	A613	A614	A615	A616	A617	A618	A619	A620	A621	A622	A623	A624	A625	A626	A627	A628	A629	A630	A631	A632	A633	A634	A635	A636	A637	A638	A639	A640	A641	A642	A643	A644	A645	A646	A647	A648	A649	A650	A651	A652	A653	A654	A655	A656	A657	A658	A659	A660	A661	A662	A663	A664	A665	A666	A667	A668	A669	A670	A671	A672	A673	A674	A675	A676	A677	A678	A679	A680	A681	A682	A683	A684	A685	A686	A687	A688	A689	A690	A691	A692	A693	A694	A695	A696	A697	A698	A699	A700	A701	A702	A703	A704	A705	A706	A707	A708	A709	A710	A711	A712	A713	A714	A715	A716	A717	A718	A719	A720	A721	A722	A723	A724	A725	A726	A727	A728	A729	A730	A731	A732	A733	A734	A735	A736	A737	A738	A739	A740	A741	A742	A743	A744	A745	A746	A747	A748	A749	A750	A751	A752	A753	A754	A755	A756	A757	A758	A759	A760	A761	A762	A763	A764	A765	A766	A767	A768	A769	A770	A771	A772	A773	A774	A775	A776	A777	A778	A779	A780	A781	A782	A783	A784	A785	A786	A787	A788	A789	A790	A791	A792	A793	A794	A795	A796	A797	A798	A799	A800	A801	A802	A803	A804	A805	A806	A807	A808	A809	A810	A811	A812	A813	A814	A815	A816	A817	A818	A819	A820	A821	A822	A823	A824	A825	A826	A827	A828	A829	A830	A831	A832	A833	A834	A835	A836	A837	A838	A839	A840	A841	A842	A843	A844	A845	A846	A847	A848	A849	A850	A851	A852	A853	A854	A855	A856	A857	A858	A859	A860	A861	A862	A863	A864	A865	A866	A867	A868	A869	A870	A871	A872	A873	A874	A875	A876	A877	A878	A879	A880	A881	A882	A883	A884	A885	A886	A887	A888	A889	A890	A891	A892	A893	A894	A895	A896	A897	A898	A899	A900	A901	A902	A903	A904	A905	A906	A907	A908	A909	A910	A911	A912	A913	A914	A915	A916	A917	A918	A919	A920	A921	A922	A923	A924	A925	A926	A927	A928	A929	A930	A931	A932	A933	A934	A935	A936	A937	A938	A939	A940	A941	A942	A943	A944	A945	A946	A947	A948	A949	A950	A951	A952	A953	A954	A955	A956	A957	A958	A959	A960	A961	A962	A963	A964	A965	A966	A967	A968	A969	A970	A971	A972	A973	A974	A975	A976	A977	A978	A979	A980	A981	A982	A983	A984	A985	A986	A987	A988	A989	A990	A991	A992	A993	A994	A995	A996	A997	A998	A999	A1000	A1001	A1002	A1003	A1004	A1005	A1006	A1007	A1008	A1009	A10010	A10011	A10012	A10013	A10014	A10015	A10016	A10017	A10018	A10019	A10020	A10021	A10022	A10023	A10024	A10025	A10026	A10027	A10028	A10029	A10030	A10031	A10032	A10033	A10034	A10035	A10036	A10037	A10038	A10039	A10040	A10041	A10042	A10043	A10044	A10045	A10046	A10047	A10048	A10049	A10050	A10051	A10052	A10053	A10054	A10055	A10056	A10057	A10058	A10059	A10060	A10061	A10062	A10063	A10064	A10065	A10066	A10067	A10068	A10069	A10070	A10071	A10072	A10073	A10074	A10075	A10076	A10077	A10078	A10079	A10080	A10081	A10082	A10083	A10084	A10085	A10086	A10087	A10088	A10089	A10090	A10091	A10092	A10093	A10094	A10095	A10096	A10097	A10098	A10099	A100100	A100101	A100102	A100103	A100104	A100105	A100106	A100107	A100108	A100109	A100110	A100111	A100112	A100113	A100114	A100115	A100116	A100117	A100118	A100119	A100120	A100121	A100122	A100123	A100124	A100125	A100126	A100127	A100128	A100129	A100130	A100131	A100132	A100133	A100134	A100135	A100136	A100137	A100138	A100139	A100140	A100141	A100142	A100143	A100144	A100145	A100146	A100147	A100148	A100149	A100150	A100151	A100152	A100153	A100154	A100155	A100156	A100157	A100158	A100159	A100160	A100161	A100162	A100163	A100164	A100165	A100166	A100167	A100168	A100169	A100170	A100171	A100172	A100173	A100174	A100175	A100176	A100177	A100178	A100179	A100180	A100181	A100182	A100183	A100184	A100185	A100186	A100187	A100188	A100189	A100190	A100191	A100192	A100193	A100194	A100195	A100196	A100197	A100198	A100199	A100200	A100201	A100202	A100203	A100204	A100205	A100206	A100207	A100208	A100209	A100210	A100211	A100212	A100213	A100214	A100215	A100216	A100217	A100218	A100219	A100220	A100221	A100222	A100223	A100224	A100225	A100226	A100227	A100228	A100229	A100230	A100231	A100232	A100233	A100234	A100235	A100236	A100237	A100238	A100239	A100240	A100241	A100242	A100243	A100244	A100245	A100246	A100247	A100248	A100249	A100250	A100251	A100252	A100253	A100254	A100255	A100256	A100257	A100258	A100259	A100260	A100261	A100262	A100263	A100264	A100265	A100266	A100267	A100268	A100269	A100270	A100271	A100272	A100273	A100274	A100275	A100276	A100277	A100278	A100279	A100280	A100281	A100282	A100283	A100284	A100285	A100286	A100287	A100288	A100289	A100290	A100291	A100292	A100293	A100294	A100295	A100296	A100297	A100298	A100

TABLE III. Gr. 00A Inspection for device type 09 - Continued.

Symbol	NLL- section	Test 3 case L	Terminal conditions and measured terminals as specified above for tpL3.												Test limits													
			1	2	3	4	5	6	7	9	10	11	12	13	14	16	17	18	19	20	21	23	24	25	26	27	28	
	Test No.	CAB	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26
tpL3	3003	310	Same terminal conditions and measured terminals as specified above for tpL3.																									
	(Fig. 4)	353																										
tpL4	3003	354	Same terminal conditions and measured terminals as specified above for tpL3.																									
	(Fig. 4)	356																										
	357																											
	358																											
	360																											
	361																											
	362																											
	363																											
	364																											
	365																											
	366																											
	367																											
	368																											
	369																											
	370		Same terminal conditions and measured terminals as specified above for tpL4.																									
	(Fig. 4)	365																										
tpZL2	3003	400	Same terminal conditions and measured terminals as specified above for tpL2.																									
	(Fig. 4)	407																										
	408																											
	409																											
	410																											
	411																											
	412																											
	413																											
	414		Same terminal conditions and measured terminals as specified above for tpL2.																									
	(Fig. 4)	417																										
tpZL2	3003	418	Same terminal conditions and measured terminals as specified above for tpL2.																									
	(Fig. 4)	419																										
	420																											
	421																											
	422																											
	423																											
	424		Same terminal conditions and measured terminals as specified above for tpL2.																									
	(Fig. 4)	419																										

See footnotes at end of table.

TABLE III. Group A Inspection for device type 09 - Continued.

Symbol	MIL-STD-883 Case 3	Terminal conditions Y												Test Items																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																	
2	3	4	5	6	7	9	10	11	12	13	14	16	17	18	19	20	21	23	24	25	26	27	28	29	30	31	32	33	34	35	36	37	38	39	40	41	42	43	44	45	46	47	48	49	50	51	52	53	54	55	56	57	58	59	60	61	62	63	64	65	66	67	68	69	70	71	72	73	74	75	76	77	78	79	80	81	82	83	84	85	86	87	88	89	90	91	92	93	94	95	96	97	98	99	100	101	102	103	104	105	106	107	108	109	110	111	112	113	114	115	116	117	118	119	120	121	122	123	124	125	126	127	128	129	130	131	132	133	134	135	136	137	138	139	140	141	142	143	144	145	146	147	148	149	150	151	152	153	154	155	156	157	158	159	160	161	162	163	164	165	166	167	168	169	170	171	172	173	174	175	176	177	178	179	180	181	182	183	184	185	186	187	188	189	190	191	192	193	194	195	196	197	198	199	200	201	202	203	204	205	206	207	208	209	210	211	212	213	214	215	216	217	218	219	220	221	222	223	224	225	226	227	228	229	230	231	232	233	234	235	236	237	238	239	240	241	242	243	244	245	246	247	248	249	250	251	252	253	254	255	256	257	258	259	260	261	262	263	264	265	266	267	268	269	270	271	272	273	274	275	276	277	278	279	280	281	282	283	284	285	286	287	288	289	290	291	292	293	294	295	296	297	298	299	300	301	302	303	304	305	306	307	308	309	310	311	312	313	314	315	316	317	318	319	320	321	322	323	324	325	326	327	328	329	330	331	332	333	334	335	336	337	338	339	340	341	342	343	344	345	346	347	348	349	350	351	352	353	354	355	356	357	358	359	360	361	362	363	364	365	366	367	368	369	370	371	372	373	374	375	376	377	378	379	380	381	382	383	384	385	386	387	388	389	390	391	392	393	394	395	396	397	398	399	400	401	402	403	404	405	406	407	408	409	410	411	412	413	414	415	416	417	418	419	420	421	422	423	424	425	426	427	428	429	430	431	432	433	434	435	436	437	438	439	440	441	442	443	444	445	446	447	448	449	450	451	452	453	454	455	456	457	458	459	460	461	462	463	464	465	466	467	468	469	470	471	472	473	474	475	476	477	478	479	480	481	482	483	484	485	486	487	488	489	490	491	492	493	494	495	496	497	498	499	500	501	502	503	504	505	506	507	508	509	510	511	512	513	514	515	516	517	518	519	520	521	522	523	524	525	526	527	528	529	530	531	532	533	534	535	536	537	538	539	540	541	542	543	544	545	546	547	548	549	550	551	552	553	554	555	556	557	558	559	560	561	562	563	564	565	566	567	568	569	570	571	572	573	574	575	576	577	578	579	580	581	582	583	584	585	586	587	588	589	590	591	592	593	594	595	596	597	598	599	600	601	602	603	604	605	606	607	608	609	610	611	612	613	614	615	616	617	618	619	620	621	622	623	624	625	626	627	628	629	630	631	632	633	634	635	636	637	638	639	640	641	642	643	644	645	646	647	648	649	650	651	652	653	654	655	656	657	658	659	660	661	662	663	664	665	666	667	668	669	670	671	672	673	674	675	676	677	678	679	680	681	682	683	684	685	686	687	688	689	690	691	692	693	694	695	696	697	698	699	700	701	702	703	704	705	706	707	708	709	710	711	712	713	714	715	716	717	718	719	720	721	722	723	724	725	726	727	728	729	730	731	732	733	734	735	736	737	738	739	740	741	742	743	744	745	746	747	748	749	750	751	752	753	754	755	756	757	758	759	760	761	762	763	764	765	766	767	768	769	770	771	772	773	774	775	776	777	778	779	780	781	782	783	784	785	786	787	788	789	790	791	792	793	794	795	796	797	798	799	800	801	802	803	804	805	806	807	808	809	8010	8011	8012	8013	8014	8015	8016	8017	8018	8019	8020	8021	8022	8023	8024	8025	8026	8027	8028	8029	8030	8031	8032	8033	8034	8035	8036	8037	8038	8039	8040	8041	8042	8043	8044	8045	8046	8047	8048	8049	8050	8051	8052	8053	8054	8055	8056	8057	8058	8059	8060	8061	8062	8063	8064	8065	8066	8067	8068	8069	8070	8071	8072	8073	8074	8075	8076	8077	8078	8079	8080	8081	8082	8083	8084	8085	8086	8087	8088	8089	8090	8091	8092	8093	8094	8095	8096	8097	8098	8099	80100	80101	80102	80103	80104	80105	80106	80107	80108	80109	80110	80111	80112	80113	80114	80115	80116	80117	80118	80119	80120	80121	80122	80123	80124	80125	80126	80127	80128	80129	80130	80131	80132	80133	80134	80135	80136	80137	80138	80139	80140	80141	80142	80143	80144	80145	80146	80147	80148	80149	80150	80151	80152	80153	80154	80155	80156	80157	80158	80159	80160	80161	80162	80163	80164	80165	80166	80167	80168	80169	80170	80171	80172	80173	80174	80175	80176	80177	80178	80179	80180	80181	80182	80183	80184	80185	80186	80187	80188	80189	80190	80191	80192	80193	80194	80195	80196	80197	80198	80199	80200	80201	80202	80203	80204	80205	80206	80207	80208	80209	80210	80211	80212	80213	80214	80215	80216	80217	80218	80219	80220	80221	80222	80223	80224	80225	80226	80227	80228	80229	80230	80231	80232	80233	80234	80235	80236	80237	80238	80239	80240	80241	80242	80243	80244	80245	80246	80247	80248	80249	80250	80251	80252	80253	80254	80255	80256	80257	80258	80259	80260	80261	80262	80263	80264	80265	80266	80267	80268	80269	80270	80271	80272	80273	80274	80275	80276	80277	80278	80279	80280	80281	80282	80283	80284	80285	80286	80287	80288	80289	80290	80291	80292	80293	80294	80295	80296	80297	80298	80299	80300	80301	80302	80303	80304	80305	80306	80307	80308	80309	80310	80311	80312	80313	80314	80315	80316	80317	80318	80319	80320	80321	80322	80323	80324	80325	80326	80327	80328	80329	80330	80331	80332	80333	80334	80335	80336	80337	80338	80339	80340	80341	80342	80343	80344	80345	80346	80347	80348	80349	80350	80351	80352	80353	80354	80355	80356	80357	80358	80359	80360	80361	80362	80363	80364	80365	80366	80367	80368	80369	80370	80371	80372	80373	80374	80375	80376	80377	80378	80379	80380	80381	80382	80383	80384	80385	80386	80387	80388	80389	80390	80391	80392	80393	80394	80395	80396	80397	80398	80399	80400	80401	80402	80403	80404	80405	80406	80407	80408	80409	80410	80411	80412	80413	80414	80415	80416	80417	80418	80419	80420	80421	80422	80423	80424	80425	80426	80427	80428	80429	80430	80431	80432	80433	80434	80435	80436	80437	80438	80439	80440	80441	80442	80443	80444	80445	80446	80447	80448	80449	80450	80451	80452	80453	80454	80455	80456	80457	80458	80459	80460	80461	80462	80463	80464	80465	80466	80467	80468	80469	80470	80471	80472	80473	80474	80475	80476	80477	80478	80479	80480	80481	80482	80483	80484	80485	80486	80487	80488	80489	80490	80491	80492	80493	80494	80495	80496	80497	80498	80499	80500</th

TABLE III. Group A inspection for device type 53.

Symbol MIL- method	Cases 2, R	Operational conditions V												Test limits		Measured subgroup 1 terminal $I_C = +25^\circ\text{C}$		Subgroup 2 $I_C = +125^\circ\text{C}$		Subgroup 3 $I_C = -55^\circ\text{C}$		Unit				
		1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	Min	Max	Min	Max	
I_{VC} (pos)	1	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	1 mA	0.4	1.5	-	-	V
	2	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	3	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	4	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	5	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	6	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	7	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	8	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	9	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	10	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	11	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	12	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	13	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	14	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	15	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	16	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	17	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	18	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	19	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	20	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	21	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	22	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	23	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	24	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	25	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	26	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	27	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	28	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	29	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	30	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	31	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	32	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	33	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	34	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	35	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	36	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	37	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	38	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	39	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	40	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	41	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	I_{CCZ}	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	42	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	43	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	44	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
	45	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-

See footnotes at end of table.

TABLE III. Group A Inspection for device type S3 - Continued.

Symbol	MIL-STD-883 Cases 2, 3, 4, 5, 6, 7, 8, 9, 10, 11, 12, 13, 14, 15, 16, 17, 18, 19, 20	Test Results										Unit	
		Measured terminal voltage, V _{TC}		Measured terminal current, I _{TC}		Subgroup 1, TC = 25°C		Subgroup 2, TC = +125°C		Subgroup 3, TC = 55°C		Unit	
MIL-STD-883 Method R	Test No.	A1	A2	A3	A4	A5	A6	A7	A8	I _{TC} min	I _{TC} max	V _{TC} min	V _{TC} max
V_{DH6}													
3006	46	0.0 V	-20 μ A	-20 μ A	-20 μ A	-20 μ A	-20 μ A	-20 μ A	-20 μ A	-20 μ A	-20 μ A	0.5 V	4.5 V
	47	-	-	-	-	-	-	-	-	-	-	-	-
	48	-	-	-	-	-	-	-	-	-	-	-	-
	50	-	-	-	-	-	-	-	-	-	-	-	-
	51	-	-	-	-	-	-	-	-	-	-	-	-
	52	-	-	-	-	-	-	-	-	-	-	-	-
	53	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V
	54	-	-	-	-	-	-	-	-	-	-	-	-
	55	-	-	-	-	-	-	-	-	-	-	-	-
	56	-	-	-	-	-	-	-	-	-	-	-	-
	57	-	-	-	-	-	-	-	-	-	-	-	-
	58	-	-	-	-	-	-	-	-	-	-	-	-
	59	-	-	-	-	-	-	-	-	-	-	-	-
	60	-	-	-	-	-	-	-	-	-	-	-	-
	61	-	-	-	-	-	-	-	-	-	-	-	-
	62	0.0 V	-6.0 mA	-6.0 mA	-6.0 mA	-6.0 mA	-6.0 mA	-6.0 mA	-6.0 mA	-6.0 mA	-6.0 mA	0.5 V	4.5 V
	63	-	-	-	-	-	-	-	-	-	-	-	-
	64	-	-	-	-	-	-	-	-	-	-	-	-
	65	-	-	-	-	-	-	-	-	-	-	-	-
	66	-	-	-	-	-	-	-	-	-	-	-	-
	67	-	-	-	-	-	-	-	-	-	-	-	-
	68	-	-	-	-	-	-	-	-	-	-	-	-
	69	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V
	70	-	-	-	-	-	-	-	-	-	-	-	-
	71	-	-	-	-	-	-	-	-	-	-	-	-
	72	-	-	-	-	-	-	-	-	-	-	-	-
	73	-	-	-	-	-	-	-	-	-	-	-	-
	74	-	-	-	-	-	-	-	-	-	-	-	-
	75	-	-	-	-	-	-	-	-	-	-	-	-
	76	-	-	-	-	-	-	-	-	-	-	-	-
	77	-	-	-	-	-	-	-	-	-	-	-	-
	78	-	-	-	-	-	-	-	-	-	-	-	-
	79	0.0 V	20 μ A	20 μ A	20 μ A	20 μ A	20 μ A	20 μ A	20 μ A	20 μ A	20 μ A	0.0 V	0.0 V
	80	-	-	-	-	-	-	-	-	-	-	-	-
	81	-	-	-	-	-	-	-	-	-	-	-	-
	82	-	-	-	-	-	-	-	-	-	-	-	-
	83	-	-	-	-	-	-	-	-	-	-	-	-
	84	-	-	-	-	-	-	-	-	-	-	-	-
	85	-	-	-	-	-	-	-	-	-	-	-	-
	86	2.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V	0.0 V
	87	-	-	-	-	-	-	-	-	-	-	-	-
	88	-	-	-	-	-	-	-	-	-	-	-	-
	89	-	-	-	-	-	-	-	-	-	-	-	-
	90	-	-	-	-	-	-	-	-	-	-	-	-
	91	-	-	-	-	-	-	-	-	-	-	-	-
	92	-	-	-	-	-	-	-	-	-	-	-	-
	93	-	-	-	-	-	-	-	-	-	-	-	-

See footnotes at end of table.

TABLE III. Group A Inspection for device type 53 - Continued.

Symbol	MIL-STD-883 Cases 2, method R	Terminal conditions 27												Test limits												
		Measured						Subgroup 1						Subgroup 2						Subgroup 3						
		Test No.	DIN	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	B6	B7	B8	B9	B10	C	N.C.	T _C = +25°C	T _C = +125°C	T _C = -55°C	Unit		
Vol. 7	3007	94	.8 V	6.0 mA	6.0 mA	6.0 mA	6.0 mA	6.0 mA	6.0 mA	86	85	84	83	82	C	N.C.	Min	Max	Min	Max	Min	Max				
		95	96	97	98	99	100	101	102	103	104	105	106	107	108	109										
I _{IN}	3011	110	111	112	113	114	115	116	117	118	119	120	121	122	123	124	125									
I _{IN} /I _{22N}		126	.8 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/	2/
		127	128	129	130	131	132	133	134	135	136	137	138	139	140	141										

See footnotes at end of table.

TABLE III. Group A inspection for device type S3 - Continued.

Symbol	MIL-STD-883 Cases 2, 3, 4, 5, 6, 7, 8, 9, 10, 11, 12, 13, 14, 15, 16, 17, 18, 19, 20	Test results																		
		Test no.	ULN	A1	A2	A3	A4	A5	A6	A7	A8	ULD	ULB	ULC	ULD	ULD	ULF	ULG	ULH	ULI
I ₁₁ / U ₁₁	142 .0 V GND																			
	143 .0 V GND																			
	144 .0 V GND																			
	145 .0 V GND																			
	146 .0 V GND																			
	147 .0 V GND																			
	148 .0 V GND																			
	149 .0 V GND																			
	150 .0 V GND																			
	151 .0 V GND																			
	152 .0 V GND																			
	153 .0 V GND																			
	154 .0 V GND																			
	155 .0 V GND																			
	156 .0 V GND																			
	157 .0 V GND																			
I ₁₁	3010 158 5.5 V																			
	3011 159 5.5 V																			
I ₁₁	3009 160 GND																			
C ₁₁ /R ₁₀	162 .0 V GND																			
	163 .0 V GND																			
	164 .0 V GND																			
	165 .0 V GND																			
	166 .0 V GND																			
	167 .0 V GND																			
	168 .0 V GND																			
	169 .0 V GND																			
	170 .0 V GND																			
	171 .0 V GND																			
	172 .0 V GND																			
	173 .0 V GND																			
	174 .0 V GND																			
	175 .0 V GND																			
	176 .0 V GND																			
	177 .0 V GND																			
C ₁₁	178 .0 V GND																			
	179 .0 V GND																			

See footnotes at end of table.

Test results

Subgroup 7		Subgroup 8		Subgroup 9		Subgroup 10	
IC = +25°C	IC = +125°C	IC = +25°C	IC = +125°C	IC = +25°C	IC = +125°C	IC = +25°C	IC = +125°C
4in	4in	4in	4in	4in	4in	4in	4in

TABLE III. Group A Inspection for device type 53 - Continued.

Symbol Method	MIL-STD-883 Cases 2, R	Terminal Conditions 17												Test Values												
		1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	Measured Terminal 9 TC = 25°C	Subgroup 10 TC = 125°C	Subgroup 11 TC = 55°C	Unit	
Test No.	DIR	A1	A2	A3	A4	A5	A6	A7	AS	CMD	BS	B7	B6	B5	B4	B3	B2	B1	T	VCC	Min	Max	Min	Max		
t _{TM} (Fig. 4)	3004	185	END	OUT	OUT	OUT	OUT	OUT	CMD	IN	IN	IN	IN	IN	IN	IN	IN	4.5 V	A1	2	12	25	
	186	A2	
	187	A3	
	188	A4	
	189	A5	
	190	A6	
	191	A7	
	192	A8	
	193	4.5 V	IN	IN	IN	IN	IN	IN	IN	IN	IN	IN	IN	IN	IN	IN	IN	IN	IN	IN	4.5 V	A1	2	12	25	
	194	A2	
	195	A3	
	196	A4	
	197	A5	
	198	A6	
	199	A7	
	200	A8	
t _{TM} (Fig. 4)	3004	201	Same tests, terminal conditions, and limits as specified above for t _{TM} . to 216												Same tests, terminal conditions, and limits as specified above for t _{TM} .											
t _{TM} (Fig. 4)	3003	217	4.5 V	IN	IN	IN	IN	IN	IN	IN	4.5 V	A1	2	12	25											
	218	A2		
	219	A3		
	220	A4		
	221	A5		
	222	A6		
	223	A7		
	224	A8		
	225	A9		
	226	A10		
	227	A11		
	228	A12		
	229	A13		
	230	A14		
	231	A15		
	232	A16		
t _{TM} (Fig. 4)	3003	223	Same terminal conditions and measured terminals as specified above for t _{TM} . to 216												Same terminal conditions and measured terminals as specified above for t _{TM} . to 216											

See footnotes at end of table.

TABLE III. Group A Inspection for device type S2 - Continued.

Symbol Method	MIL- STD-883C Cases 2, 8	Terminal conditions 1/												Test results												
		1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	measured	Subgroup J IC = +125°C g/	Subgroup J IC = +125°C g/	Subgroup J IC = +125°C g/	Test limit
t_{p2H}	3003 (Fig. 4)	249	GND	OUT	OUT	OUT	OUT	OUT	OUT	OUT	OUT	4.5 V	10 A1	6	41	41										
<u>10/</u>	250	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A2	-	-	-
<u>251</u>	252	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A3	-	-	-
<u>253</u>	254	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A4	-	-	-
<u>255</u>	256	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A5	-	-	-
<u>257</u>	258	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	10 A6	-	-	-
<u>259</u>	260	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A7	-	-	-
<u>261</u>	262	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A8	-	-	-
<u>263</u>	264	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A9	-	-	-
<u>265</u>	266	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A10	-	-	-
<u>267</u>	268	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A11	-	-	-
<u>269</u>	270	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A12	-	-	-
<u>271</u>	272	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A13	-	-	-
<u>273</u>	274	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A14	-	-	-
<u>275</u>	276	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A15	-	-	-
<u>277</u>	278	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A16	-	-	-
<u>279</u>	280	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A17	-	-	-
<u>281</u>	282	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A18	-	-	-
<u>283</u>	284	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A19	-	-	-
<u>285</u>	286	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A20	-	-	-
<u>287</u>	288	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A21	-	-	-
<u>289</u>	290	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A22	-	-	-
<u>291</u>	292	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A23	-	-	-
<u>293</u>	294	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A24	-	-	-
<u>295</u>	296	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A25	-	-	-
<u>297</u>	298	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A26	-	-	-
<u>299</u>	300	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A27	-	-	-
<u>301</u>	302	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A28	-	-	-
<u>303</u>	304	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A29	-	-	-
<u>305</u>	306	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A30	-	-	-
<u>307</u>	308	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A31	-	-	-
<u>309</u>	310	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A32	-	-	-
<u>311</u>	312	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	10 A33	-	-	-

1/ Same terminal conditions and measured terminals as specified above for t_{p2H} .

2/ Pins not designated may be "High" level logic, "Low" level logic, or open. Exceptions are as follows:

- a. $V_{OC}(pos)$ tests, the GND terminal shall be open. A minimum limit of 0.4 V applies to tests being performed on equipment not capable of opening the GND pin during testing.
- b. $V_{OC}(neg)$ tests, the V_{CC} terminal shall be open.
- c. IC/C tests, the output terminal shall be open.

- 2/ Three-state output conditions are required. For t_{o2H} , set output to high state. For t_{o2L} , set output to low state. Set input pins to $V_L = V_H(\text{min})$ or to $V_H = V_L(\text{min})$, as required.
- 3/ See 4.4.1c.
- 4/ See 4.4.1d.
- 5/ Tests shall be performed in sequence, attributes data only.

- 6/ $H > 1.5 V$, $L < 1.5 V$, $A = 0.7 V$, $B = 0.4 V$.
- 7/ Three-state output conditions are required.
- 8/ f_{max} minimum limit specified is the frequency of the input pulse. The output frequency shall be one-half of the input frequency.

- 9/ Add 1kΩ minimum resistor between V_{CC} and output to pull output to high state.
- 10/ Add 1kΩ minimum resistor between GND and output to pull output to low state.

4.4.4 Group D inspection. Group D inspection shall be in accordance with table IV of method 5005 of MIL-STD-883. End-point electrical parameters shall be as specified in table II herein.

4.4.5 Group E inspection. Group E inspection is required only for device types intended to be marked as radiation hardened (see 3.6.1). When group E testing is performed it shall be in accordance with table V of method 5005 of MIL-STD-883 and 4.5.4 herein.

4.5 Methods of inspection. Methods of inspection shall be specified as follows:

4.5.1 Voltage and current. Unless otherwise specified, all voltages given are referenced to the microcircuit GND terminal. Currents given are conventional and positive when flowing into the referenced terminal.

4.5.2 Burn-in and life test cool down procedures. When the burn-in and life tests are completed and prior to removal of bias voltages, the devices under test (DUT) shall be cooled to within 10°C of their power stable condition at room temperature; then, electrical parameter end-point measurements shall be performed.

TABLE IV. Delta limits at 25°C.

Parameter 1/	Device types	
	ATT	
I _{CC}		±30 nA

1/ The above parameters shall be recorded before and after the required burn-in and life tests to determine deltas (Δ).

4.5.3 Quiescent supply current (I_{CC} test). When performing quiescent supply current measurements (I_{CC}), the meter shall be placed so that all currents flow through the meter.

4.5.4 Radiation hardness assurance (RHA) testing. The RHA testing shall be performed in accordance with test procedures and sampling specified in table V of method 5005 of MIL-STD-883 and herein:

- a. Before irradiation, selected samples shall be assembled in qualified packages and pass the governing electrical parameters (group A subgroup 1 at 25°C) and also be subjected to the threshold-voltage test in table V in order to calculate the delta threshold (ΔV_T) after irradiation.
- b. The devices shall be subjected to a total radiation dose as specified in MIL-M-38510 for the radiation hardness assurance (RHA) level being tested, and meet the end point electrical parameters as defined in table VI at 25°C, after exposure. The start and completion of the end point electrical parameter measurements shall not exceed 2 hours following irradiation.
- c. Threshold-voltage test circuit conditions shall be as specified in table V and figure 5. In situ and remote testing, the tests shall be performed with the devices biased in accordance with table VII and bias may be interrupted for up to 1 minute to remove devices to the remote bias fixture.
- d. After irradiation, the devices shall pass the truth table test as specified in subgroup 7 in table III or if subgroup 7 is not required, then an equivalent truth table test shall be performed.

TABLE V. Threshold-voltage test circuit conditions.

Device type	GND	5 V	V_{TN} measured at	GND	-5.0 V	V_{TP} measured at
			-20 μ A supply			20 μ A supply
01	1	14	3, 4, 5, 6, 7, 13	1	7, 8, 9, 10, 11	13, 14
02	1	14	3, 4, 5, 6, 7, 13	1	7, 8, 9, 10, 11	13, 14
03, 53	1	20	10-19	1	2-10, 19	20
04						
05						
06	1	20	10-19	1	2-10, 19	20
07	1	20	10-19	1	2-10, 19	20
08	3	24	1, 2, 12-23	3	1, 2 4-12, 21-23	24
09	3	24	1, 2, 12-23	3	1, 2 4-12, 21-23	24

TABLE VI. Radiation hardening end-point electrical parameters at +25°C.

Parameter	All device types	V_{CC}	
		01-09	53
V_{TN}	-0.3 V min	5 V	5 V
V_{TP}	2.8 V max	5 V	5 V
ΔV_T	1.0 V max	5 V	5 V
I_{CC}	100 x max limit	6 V	5.5 V
t_{PLH}	1.35 x max limit	4.5 V	4.5 V
t_{PHL}	1.35 x max limit	4.5 V	4.5 V

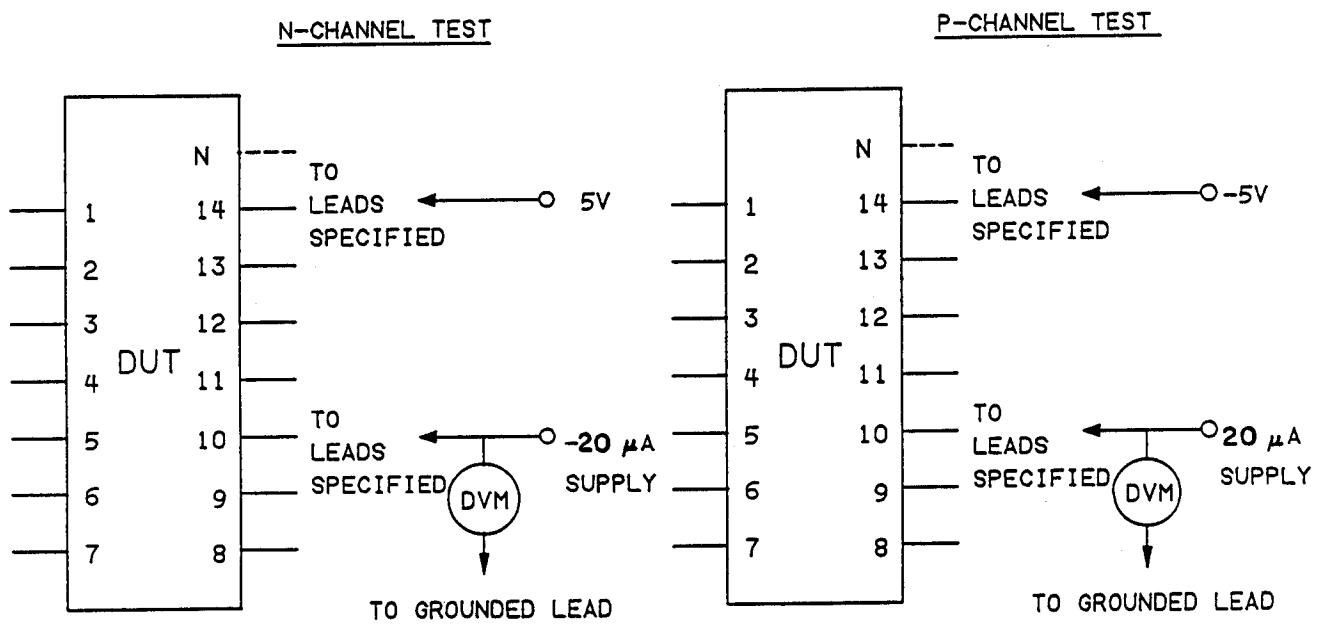
FIGURE 5. Threshold - voltage test circuit.

TABLE VII. Bias during exposure to radiation.

Device type	Pin connections		
	$V_{CC} = 4.5 \text{ V dc}$ (through a 30- to 60-kilohm resistor)	GND	$V_{CC} = 4.5 \text{ V dc}$
01	1, 8-11, 13	7	14
02	1, 8-11, 13	7	14
03, 53	11-18	1,10,19	20
04			
05			
06	11-18	1,10,19	20
07	11-18	1,10,19	20
08	1, 13-20, 23	2,3,12, 22,23	24
09	1, 13-20, 23	2,3,12, 22,23	24

Pins not designated are open or connected to 4.5 V dc through a 30- to 60-kilohm resistor.

4.6 Data reporting. When specified in the purchase order or contract, a copy of the following data, as applicable, shall be supplied.

- a. Attributes data for all screening tests (see 4.2) and variables data for all static burn-in, dynamic burn-in, and steady-state life tests (see 3.5).
- b. A copy of each radiograph.
- c. The quality conformance inspection data (see 4.4).
- d. Parameter distribution data on parameters evaluated during burn-in (see 3.5).
- e. Final electrical parameters data (see 4.2c).

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this specification are intended for original equipment design application and logistic support of existing equipment.

6.2 Ordering data. The acquisition document should specify the following:

- a. Complete part number (see 1.2).
- b. Requirements for delivery of one copy of the quality conformance inspection data pertinent to the device inspection lot to be supplied with each shipment by the device manufacturer, if applicable.

- c. Requirements for certificate of compliance, if applicable.
- d. Requirements for notification of change of product or process to the contracting activity in addition to notification to the qualifying activity, if applicable.
- e. Requirements for failure analysis (including required test condition of method 5003 of MIL-STD-883), corrective action and reporting of results, if applicable.
- f. Requirements for product assurance options.
- g. Requirements for special carriers, lead lengths, or lead forming, if applicable. These requirements shall not affect the part number. Unless otherwise specified, these requirements shall not apply to direct purchase by, or direct shipment to the Government.
- h. Requirements for "JAN" marking.

6.3 Abbreviations, symbols, and definitions. The abbreviations, symbols, and definitions used herein are defined in MIL-M-38510, MIL-STD-1331, and as follows:

GND - - - - - - - - - - - - - - - -	Ground zero voltage potential.
V _{IN} - - - - - - - - - - - - - - - -	Voltage level at an input terminal.
I _{IN} - - - - - - - - - - - - - - - -	Current flowing into an input terminal.
t _{PHZ} - - - - - - - - - - - - - - - -	Output disable time (of a three-state output) from high-level. The time between the specified reference points on the input and output voltage waveforms with the three-state output changing from the defined high-level to a high-impedance (off) state.
t _{PLZ} - - - - - - - - - - - - - - - -	Output disable time (of a three-state output) from low-level. The time between the specified reference points on the input and output voltage waveforms with the three-state output changing from the defined low-level to a high-impedance (off) state.
t _{ZH} - - - - - - - - - - - - - - - -	Output enable time (of a three-state output) to high-level. The time between the specified reference points on the input and output voltage waveforms with the three-state output changing from a high-impedance (off) state to the defined high-level.
t _{ZL} - - - - - - - - - - - - - - - -	Output enable time (of a three-state output) to low-level. The time between the specified reference points on the input and output voltage waveforms with the three-state output changing from a high-impedance (off) state to the defined low-level.

6.4 Logistic support. Lead materials and finishes (see 3.3) are interchangeable. Unless otherwise specified, microcircuits acquired for Government logistic support will be acquired to device class S for National Aeronautics and Space Administration or class B for Department of Defense (see 1.2.2), lead finish C (see 3.3). Longer length leads and lead forming shall not affect the part number.

6.5 Substitutability. The cross-reference information below is presented for the convenience of users. Microcircuits covered by this specification will functionally replace the listed generic-industry type. Generic-industry microcircuit types may not have equivalent operational performance characteristics across military temperature ranges or reliability factors equivalent to MIL-M-38510 device types and may have slight physical variations in relation to case size. The presence of this information shall not be deemed as permitting substitution of generic-industry types for MIL-M-38510 types or as a waiver of any of the provisions of MIL-M-38510.

Military device type	Generic-industry type
01	54HC242
02	54HC243
03	54HC245
04 1/	54HC620
05 I/	54HC623
06	54HC640
07	54HC643
08	54HC646
09	54HC648
53	54HCT245

1/ These device types to be included in a later revision of this specification.

6.6 Handling. MOS devices must be handled with certain precautions to avoid damage due to accumulation of static charge. Input protective devices have been designed in the chip to minimize the effect of this static build up. However, the following handling practices are recommended:

- a. Devices should be handled on benches with conductive and grounded surface.
- b. Ground test equipment and tools.
- c. Do not handle devices by the leads.
- d. Store devices in conductive foam or carriers.
- e. Avoid use of plastic, rubber, or silk in MOS areas.
- f. Maintain relative humidity above 50 percent, if practical.

Custodians:

Army - ER
Navy - EC
Air Force - 17
NASA - NA

Preparing activity:
Air Force - 17

Agent:
DLA - ES

Review activities:

Army - AR, MI
Air Force - 11, 19, 85, 99
DLA - ES

(Project 5962-0850)

User activities:

Army - SM
Navy - AS, CG, OC, MC, SH